

EWEA AFM SAMPLES

L51 (2-40) RAE [L51-1]

512 pixels

10 μm x10 μm

Image was taken with a standard Silicon Tip

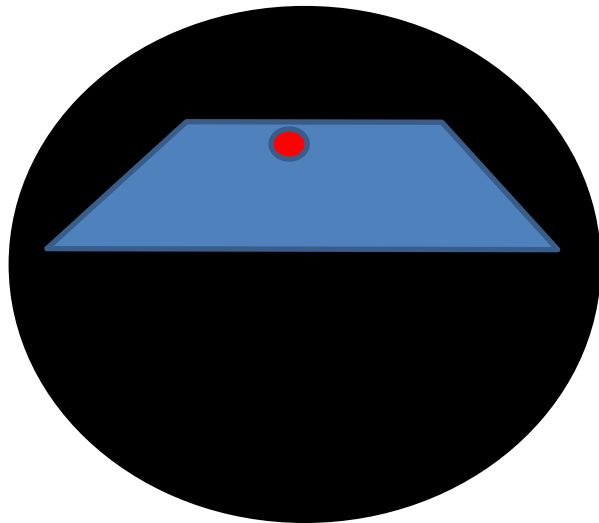
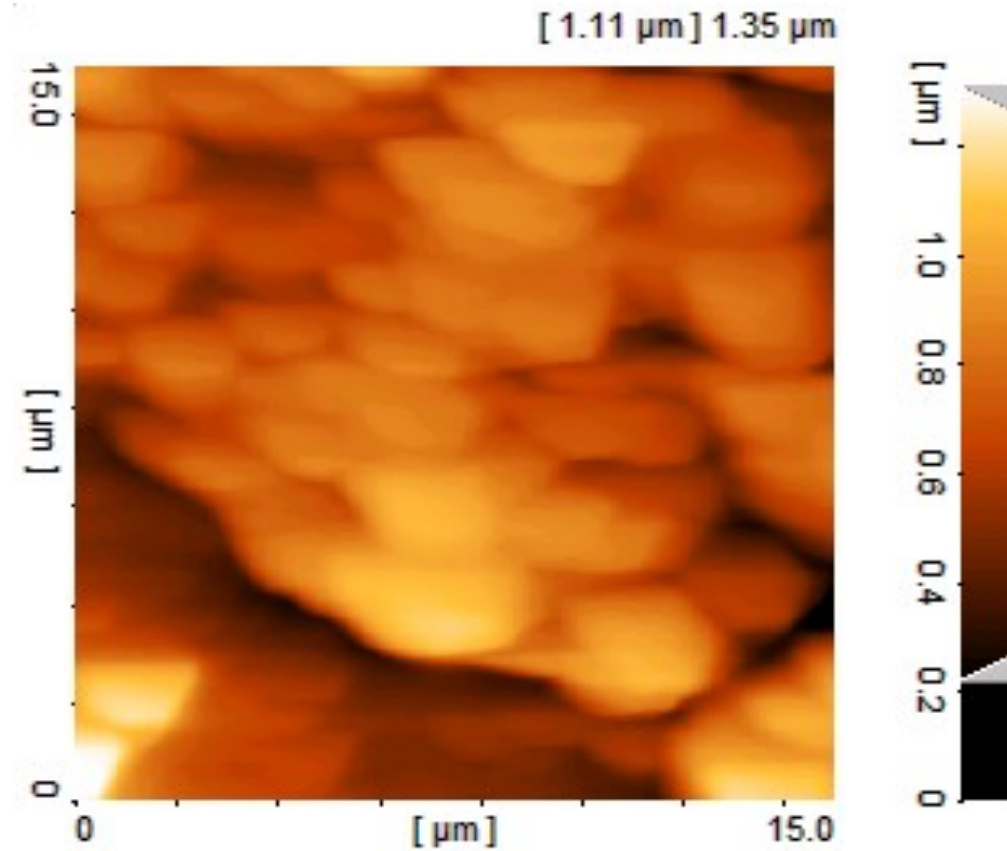


Diagram of sample on SEM stub
Red Circle indicates region of image taken by AFM.



EWEA AFM SAMPLES

L51 (2-40) RAE [L51-2]

256 pixels

20 μ m \times 20 μ m

Image was taken with a standard Silicon Tip

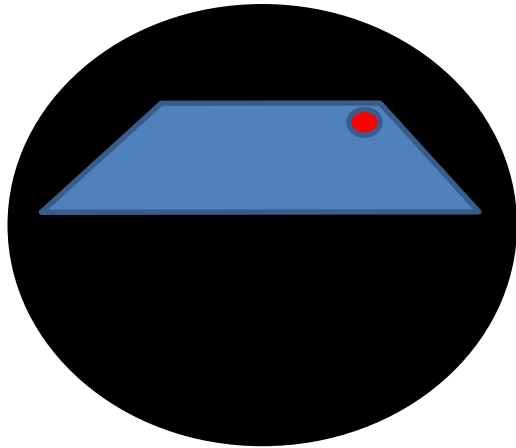
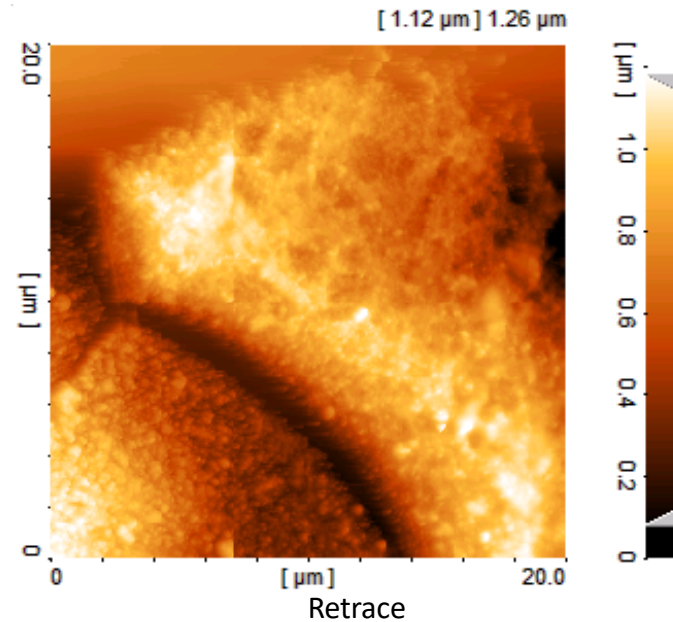
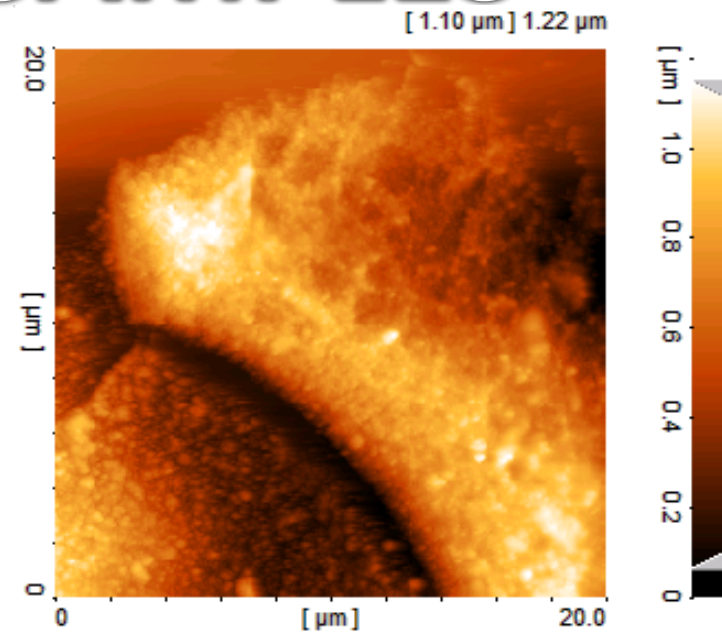
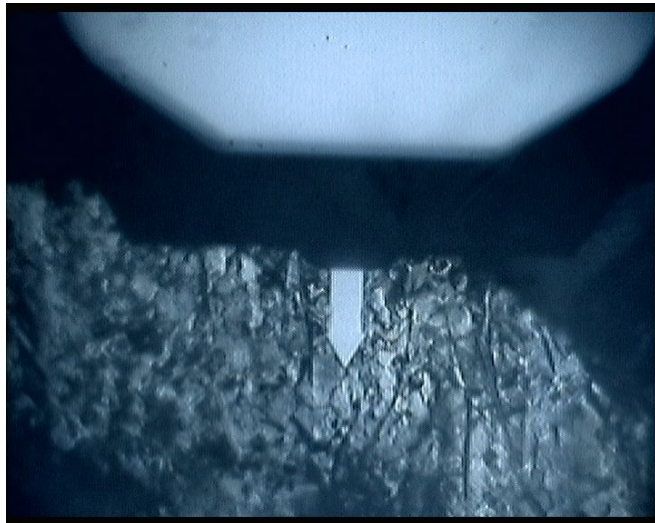
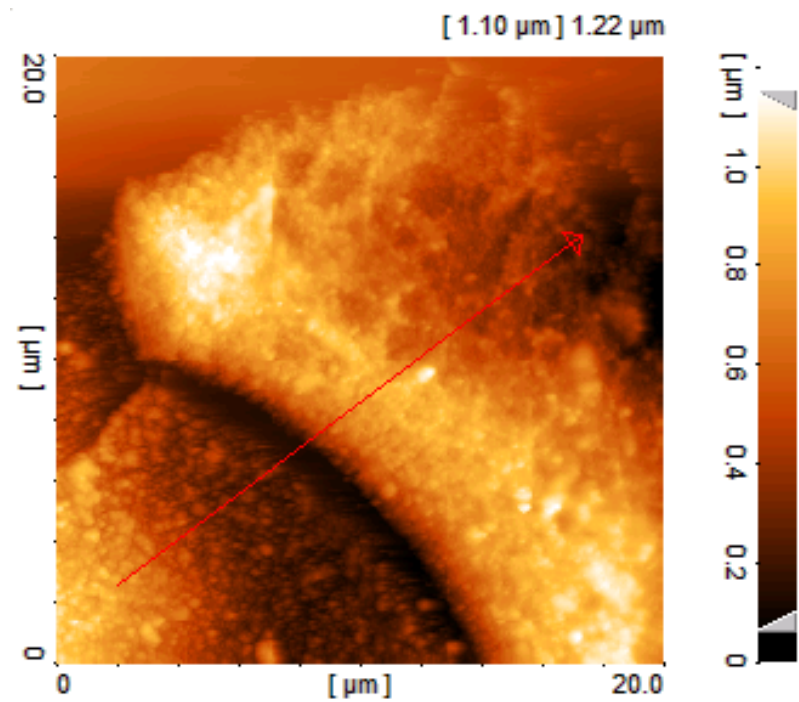


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.





EWEA AFM SAMPLES

L51 (2-40) RAE [L51-3]

256 pixels

20 μm x20 μm

Image was taken with a standard Silicon Tip

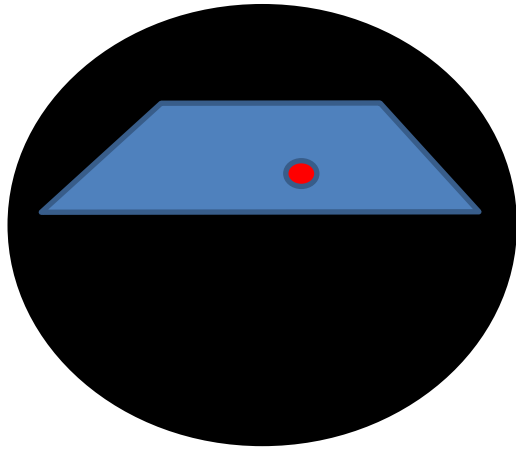
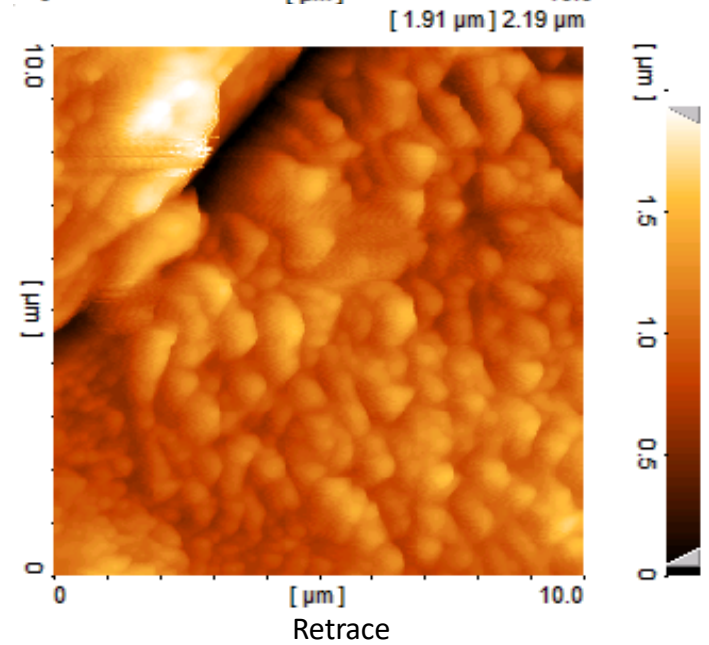
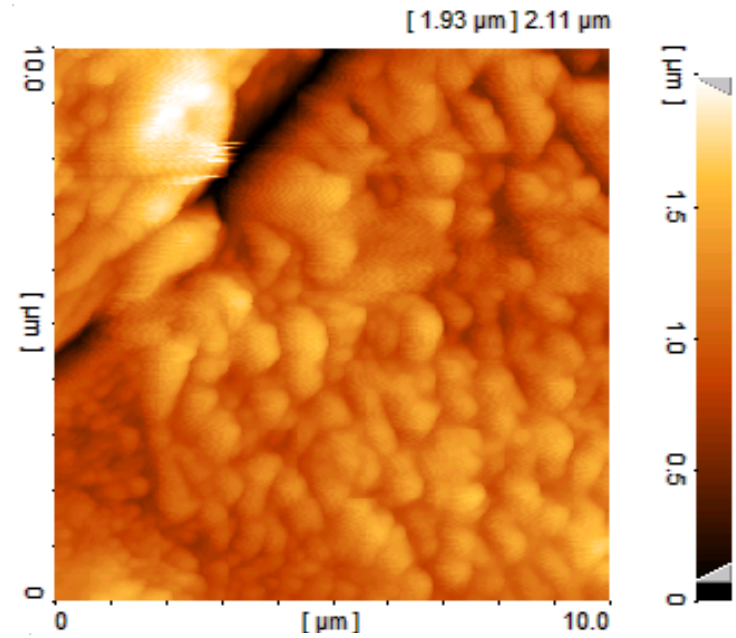
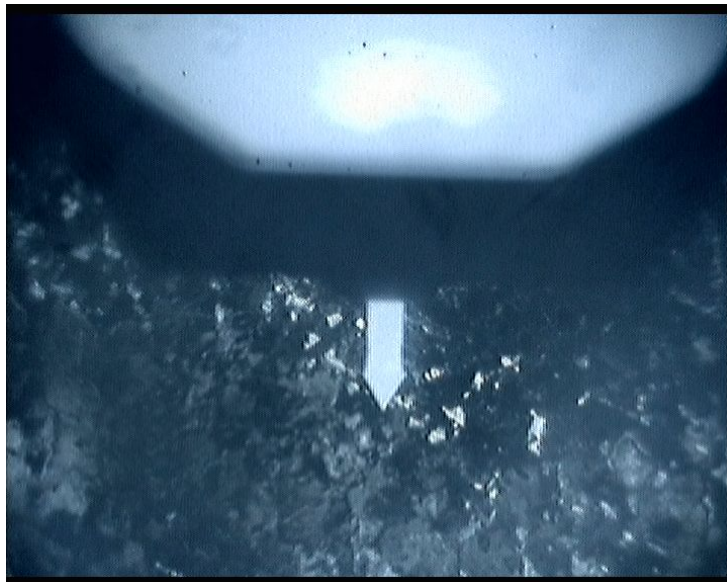


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.



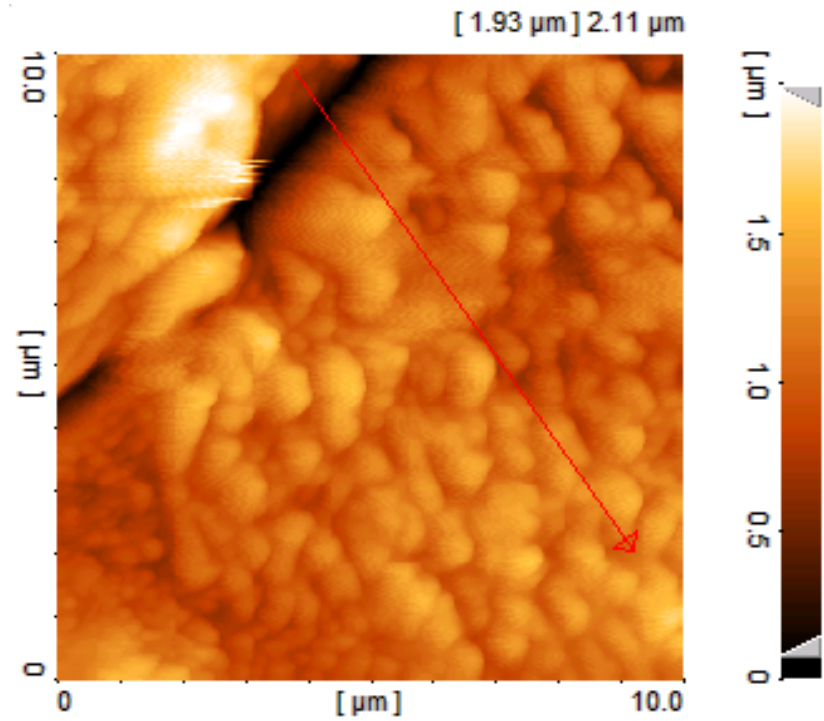
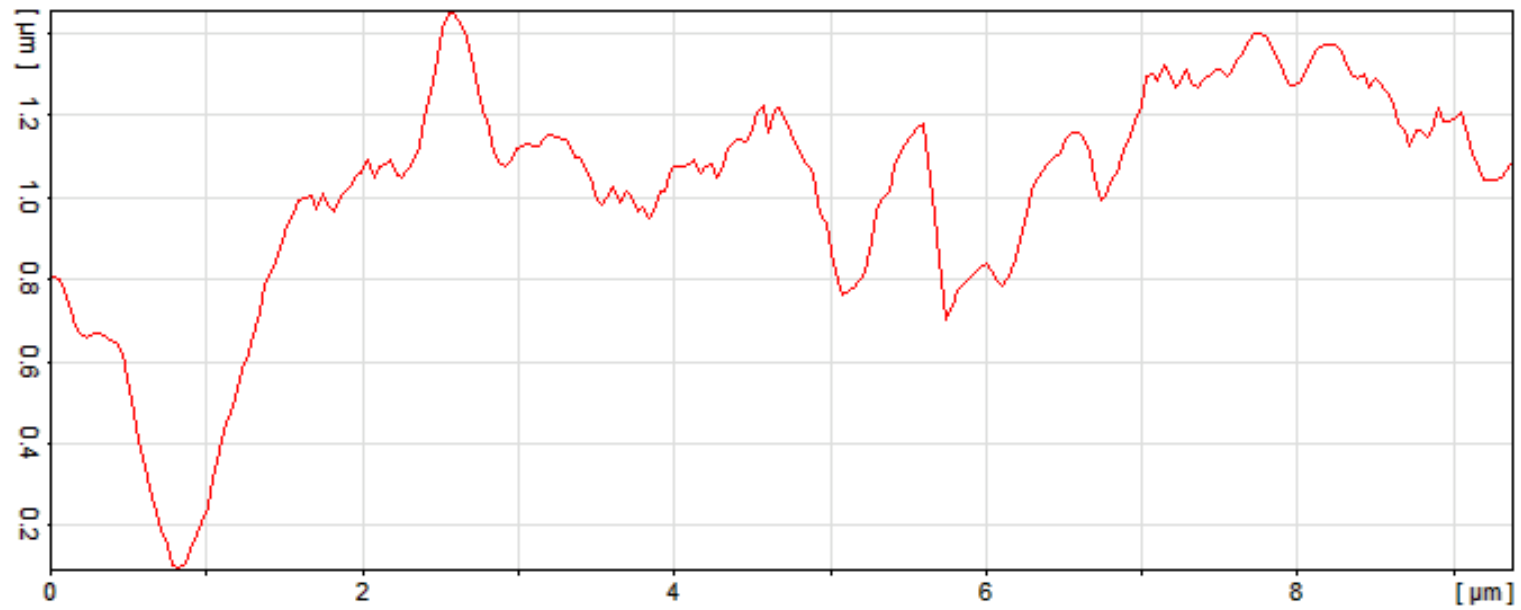


Image Profile



EWEA AFM SAMPLES

L46 (85-125) RAEF [L46-1]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

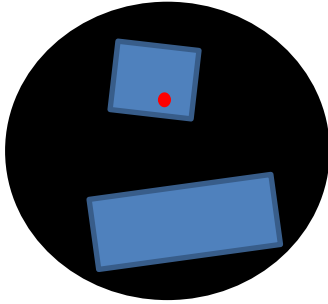
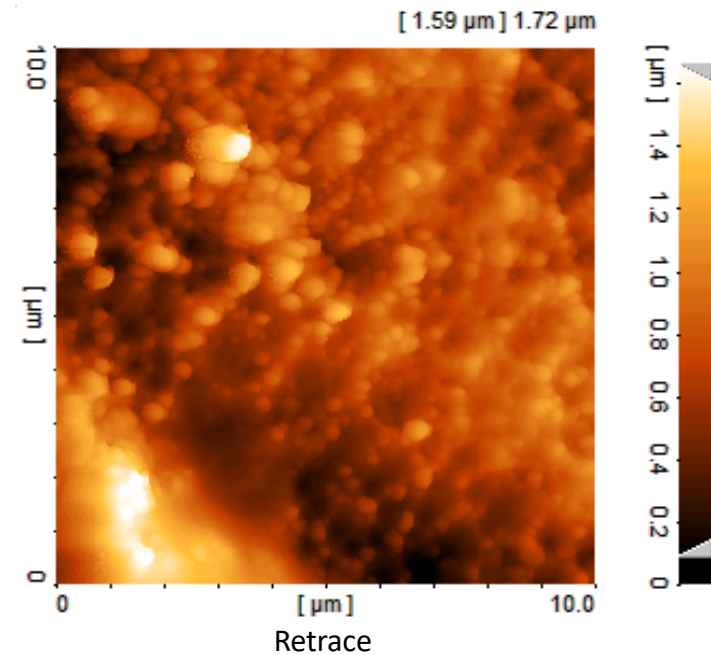
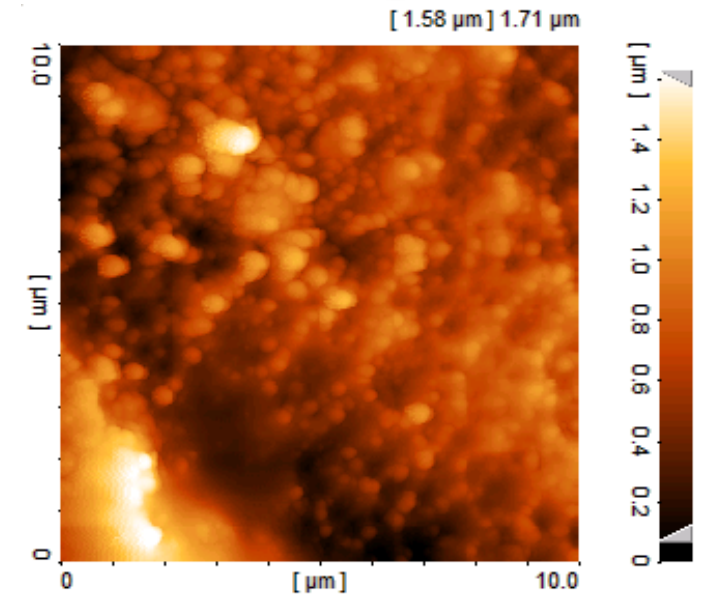
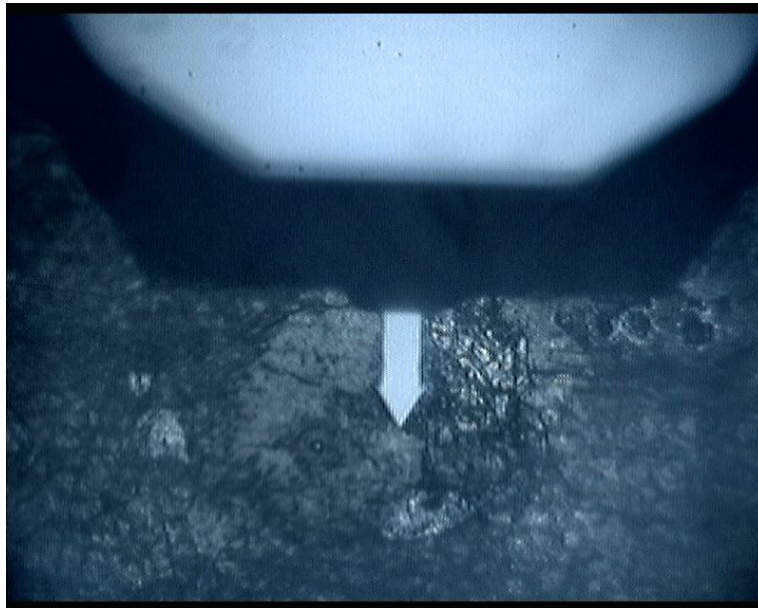
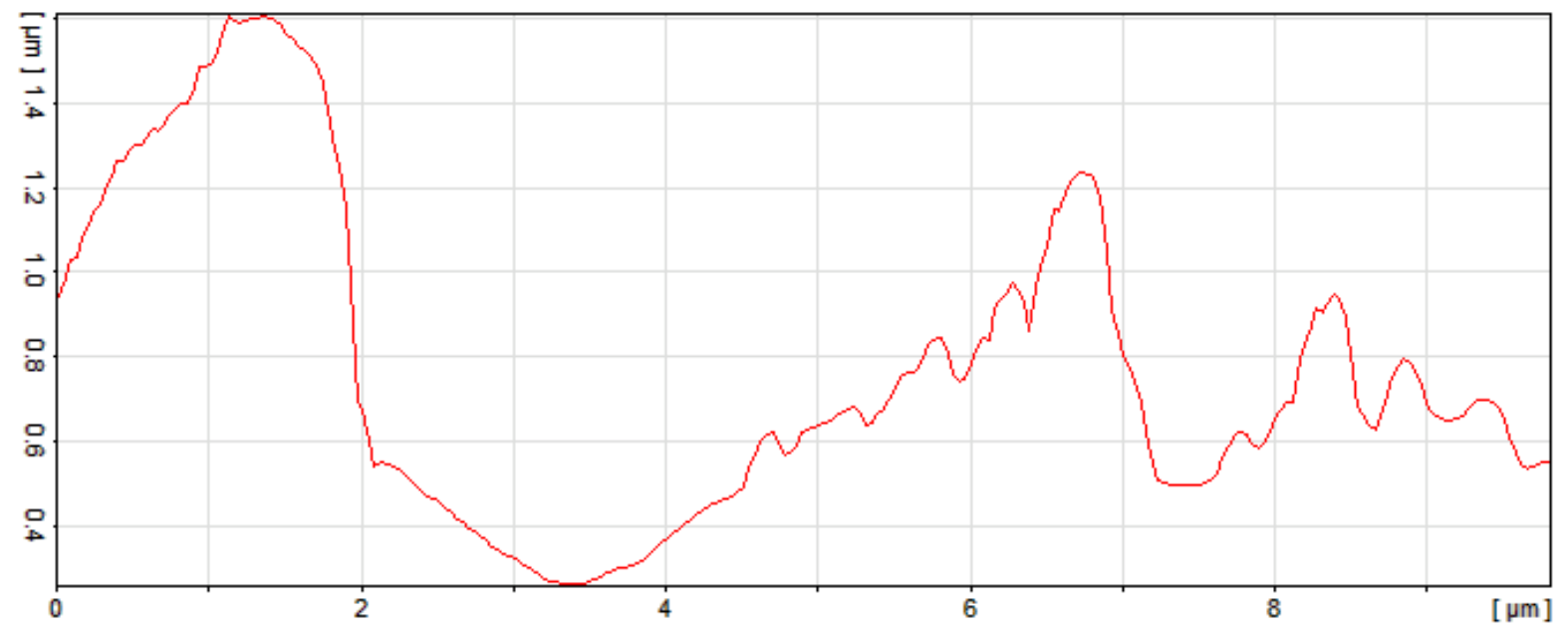
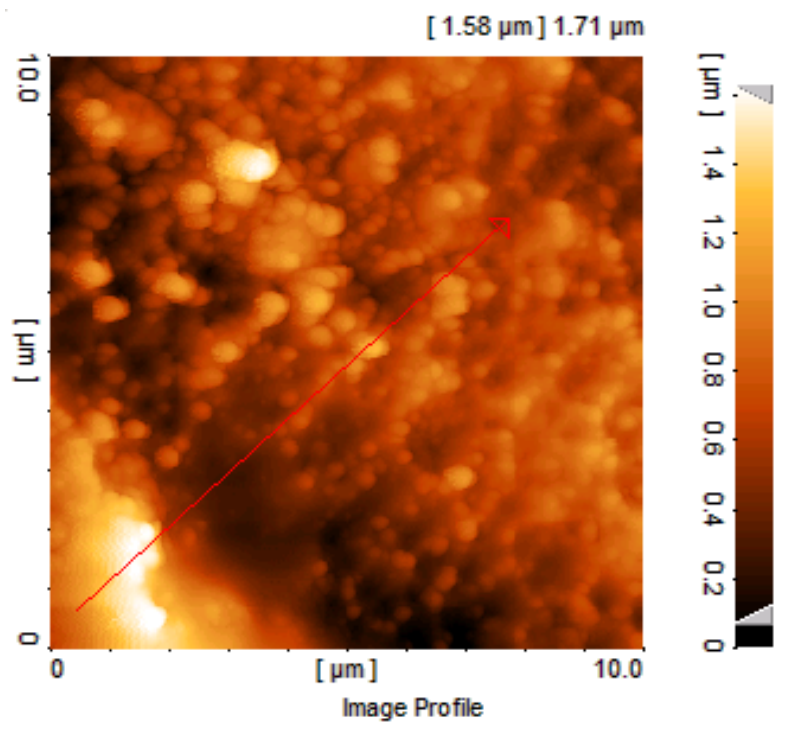


Diagram of sample on SEM stub
Red Circle indicates region of image taken by AFM.





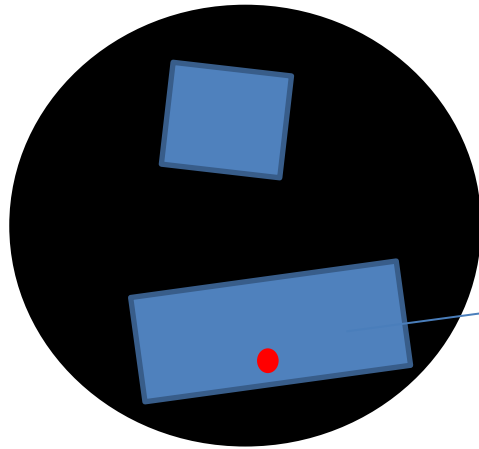
EWEA AFM SAMPLES

L46 (85-125) RAEF

512 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.



Sample slides on measurements!

Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.

EWEA AFM SAMPLES

L47 (17-97) RAE [L47-1]

512 pixels
10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

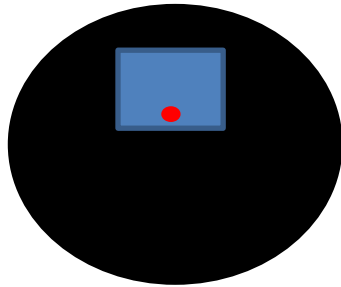
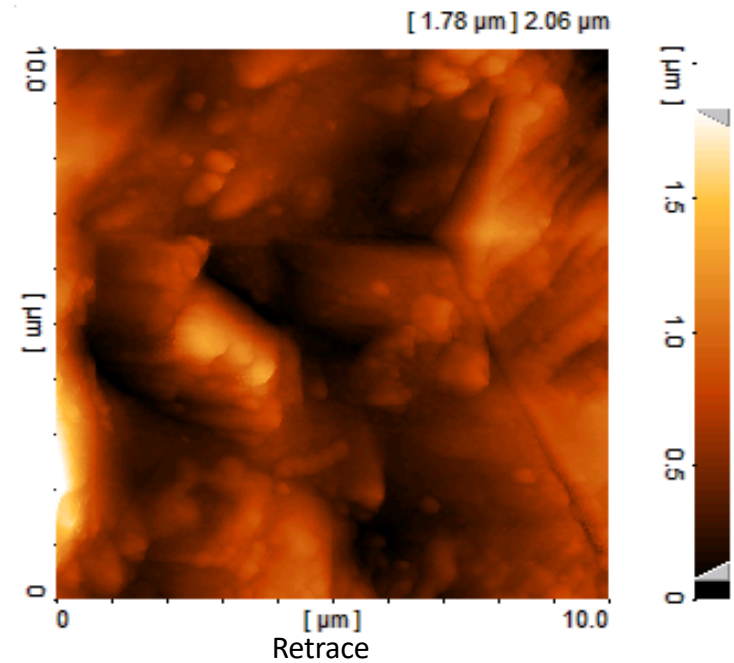
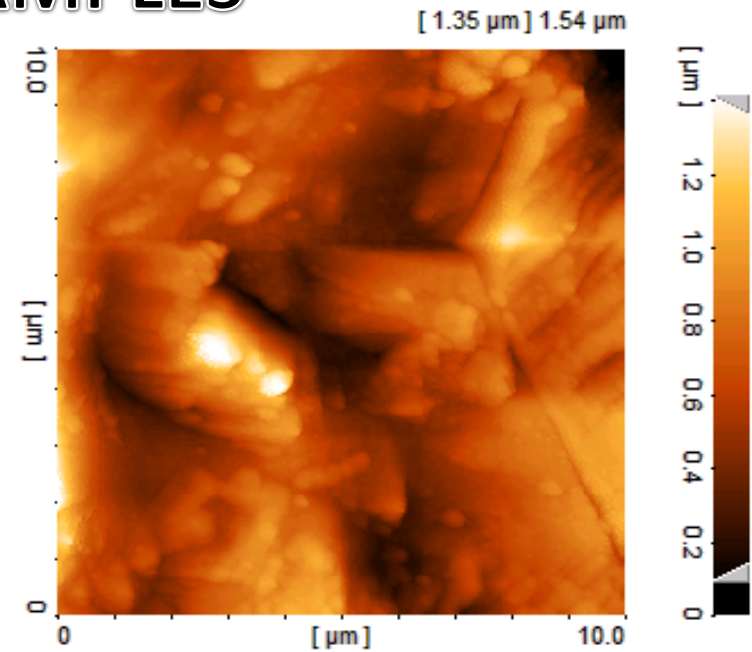
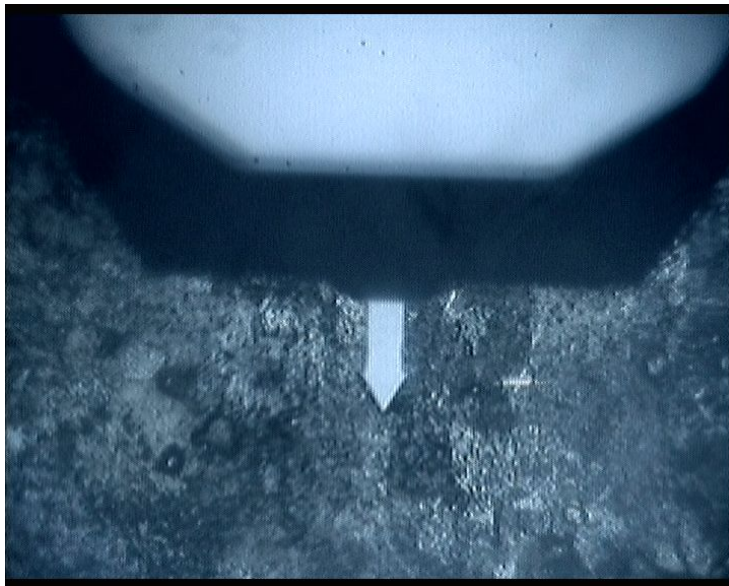
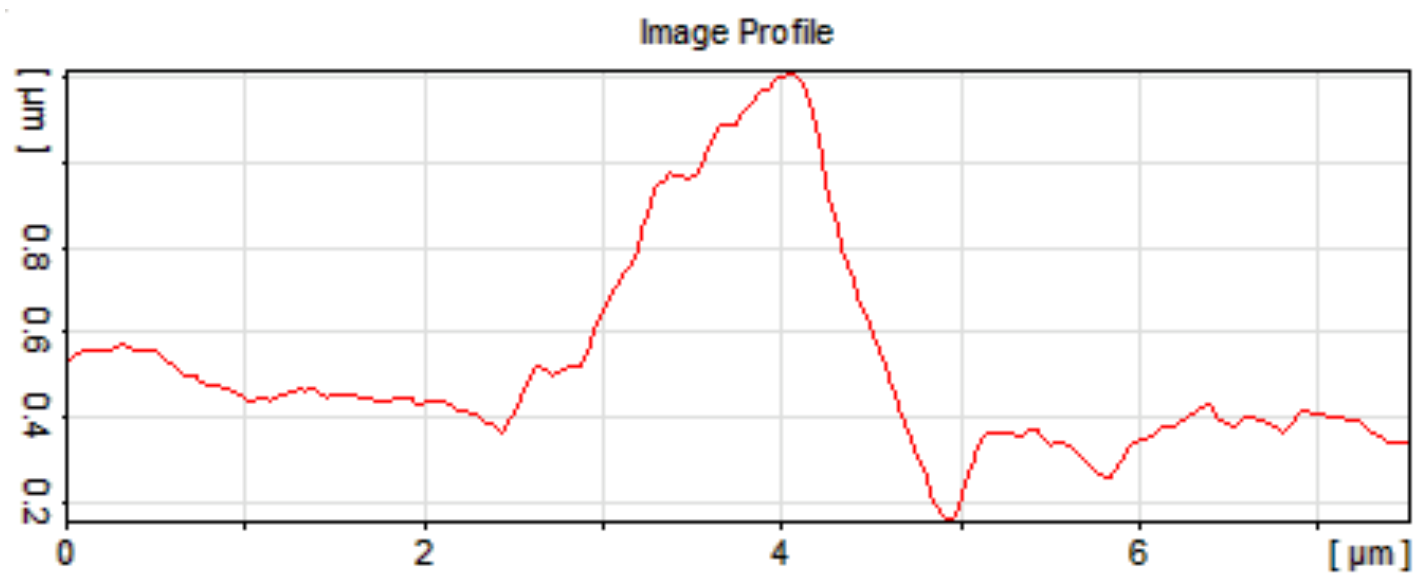
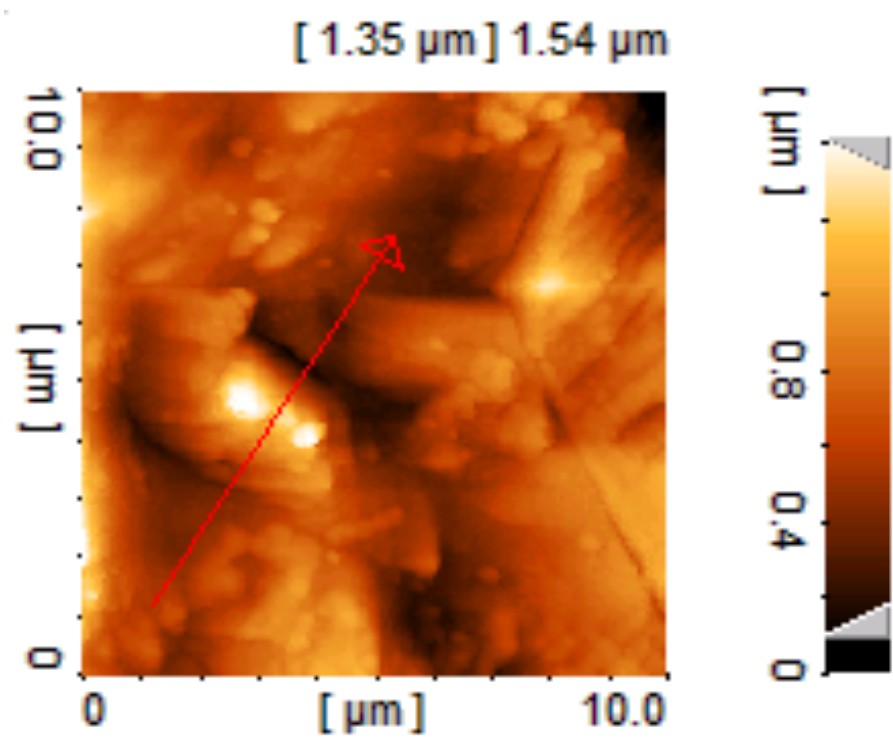


Diagram of sample on SEM stub
Red Circle indicates region of image taken by AFM.





EWEA AFM SAMPLES

L47 (17-97) RAE [L47-2]

512 pixels
10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

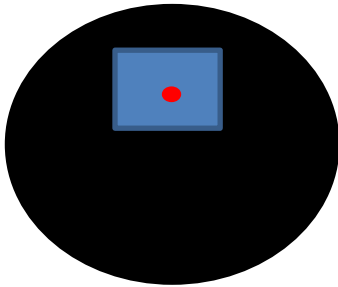
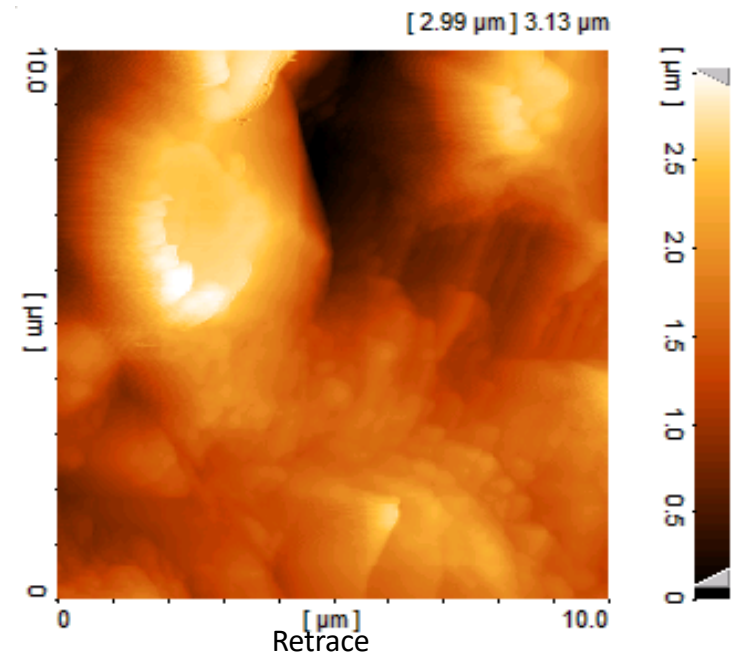
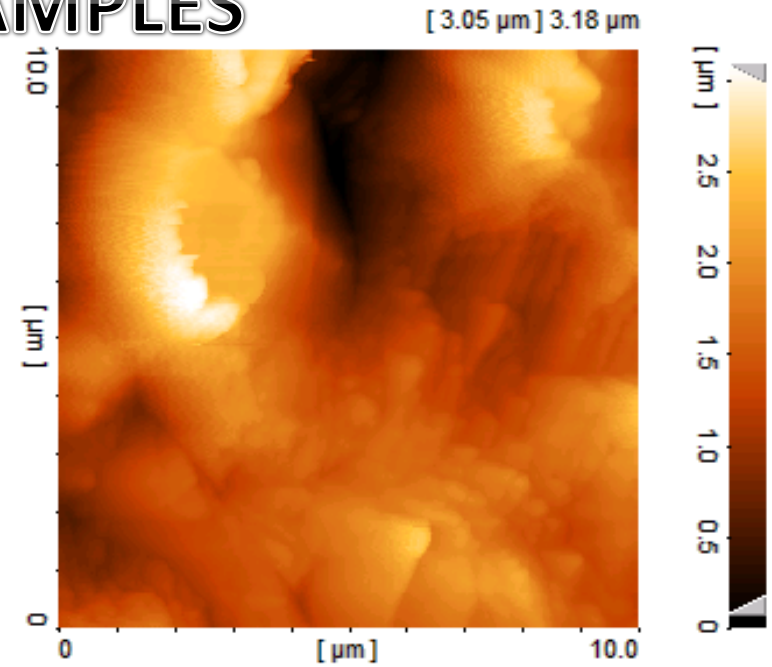
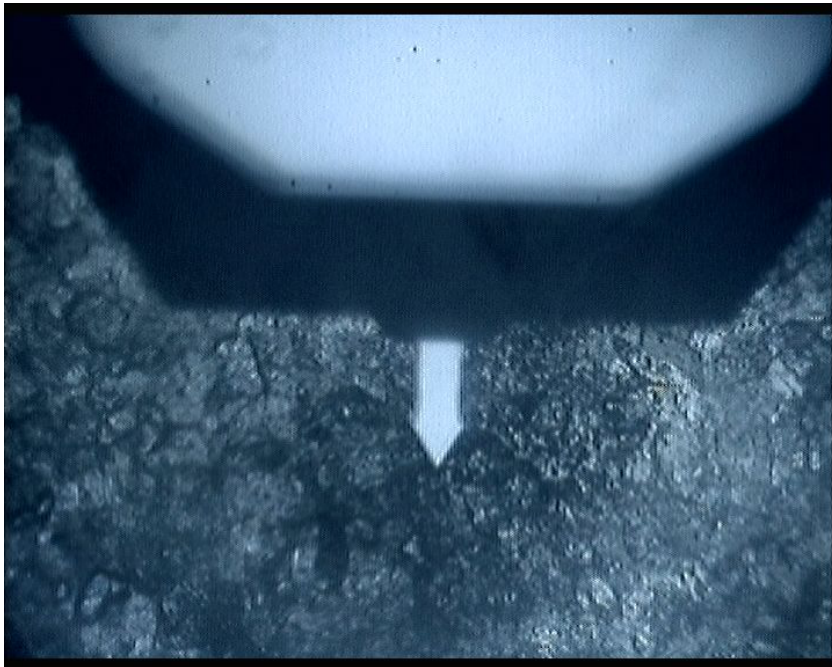
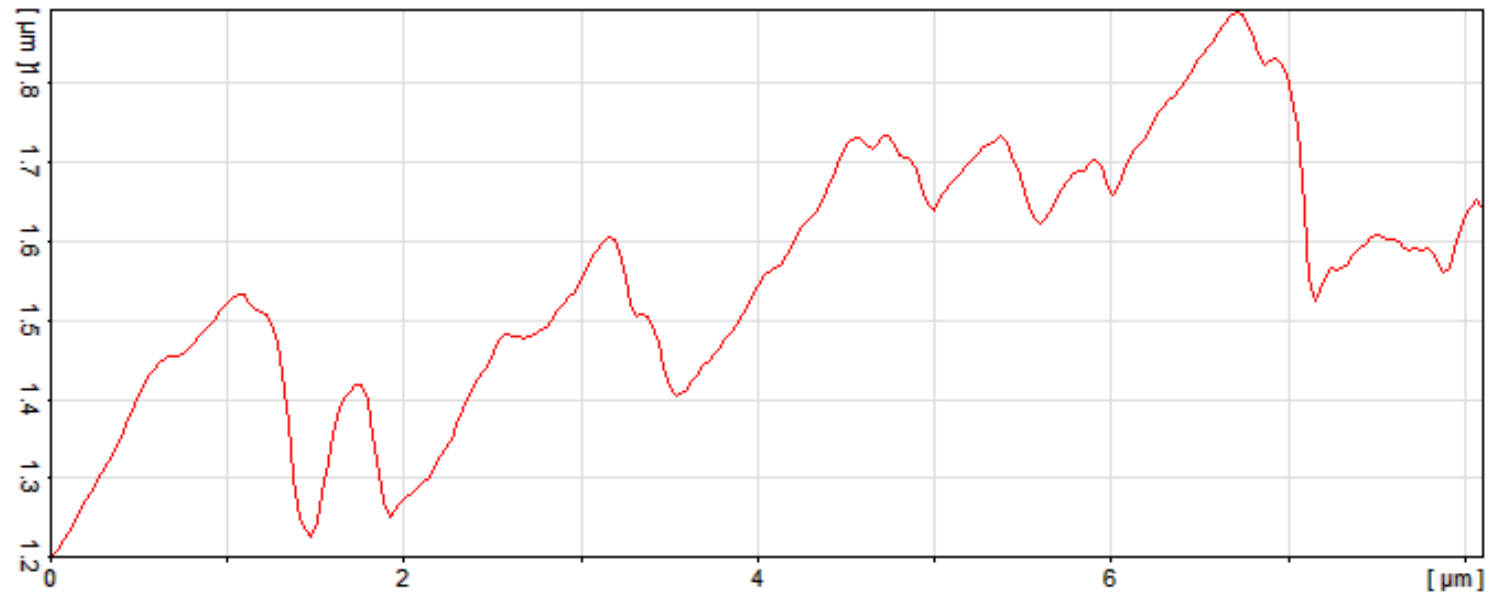
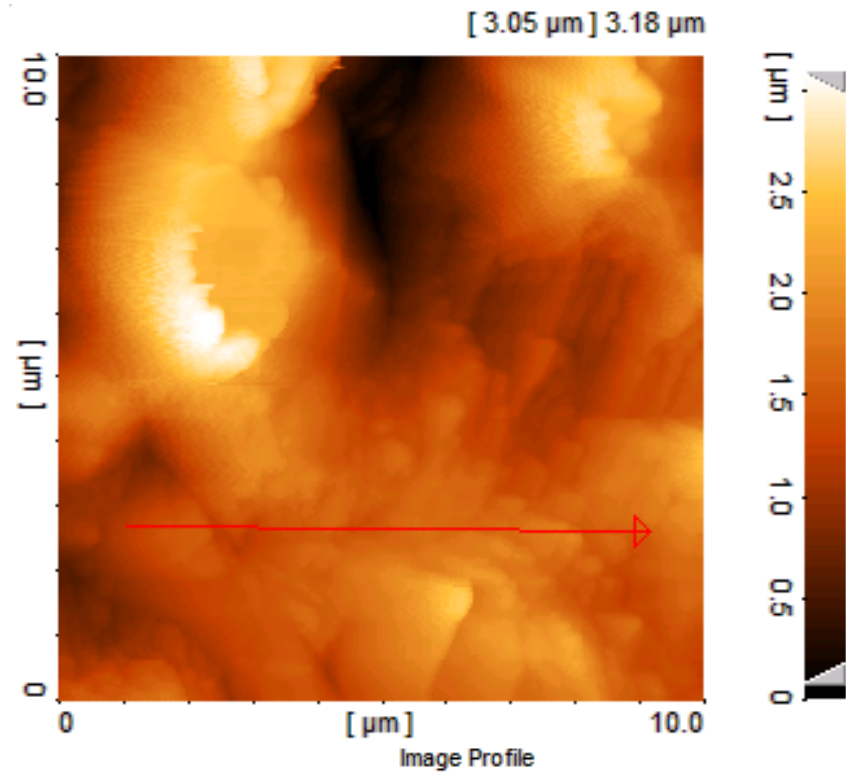


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.





EWEA AFM SAMPLES

L53 (260-301) RAE [L53-1]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

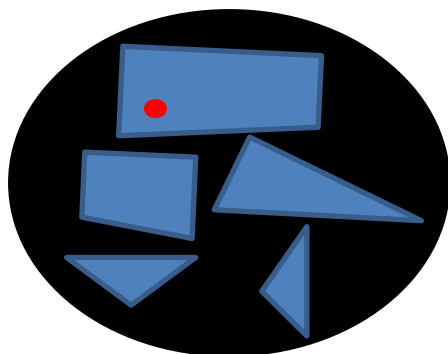
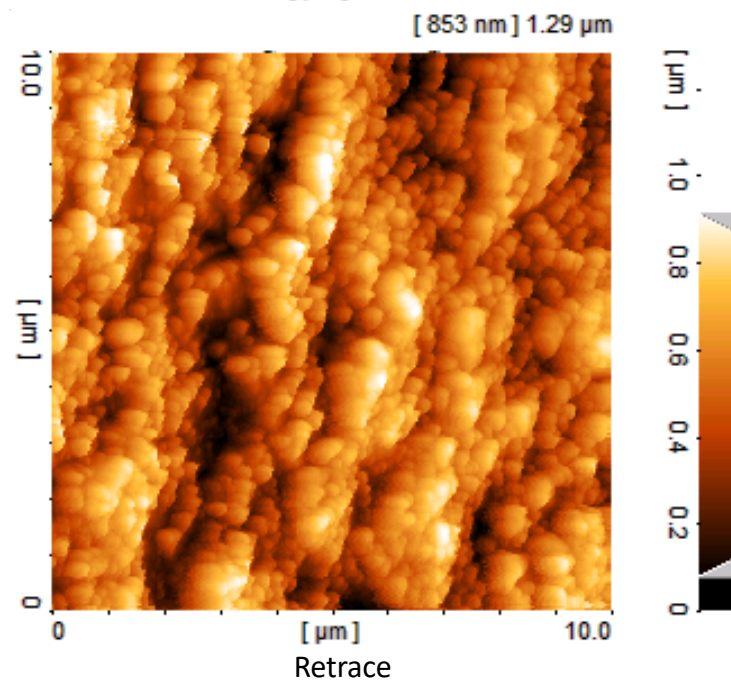
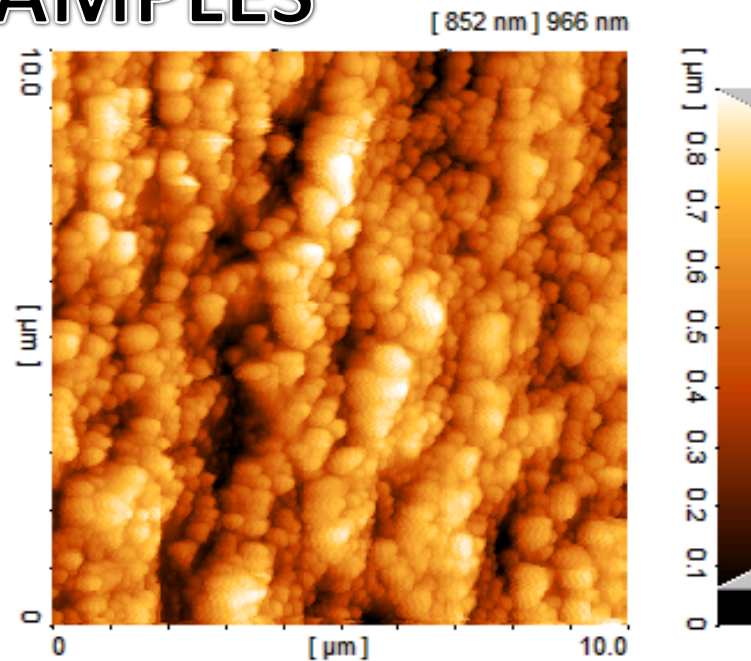
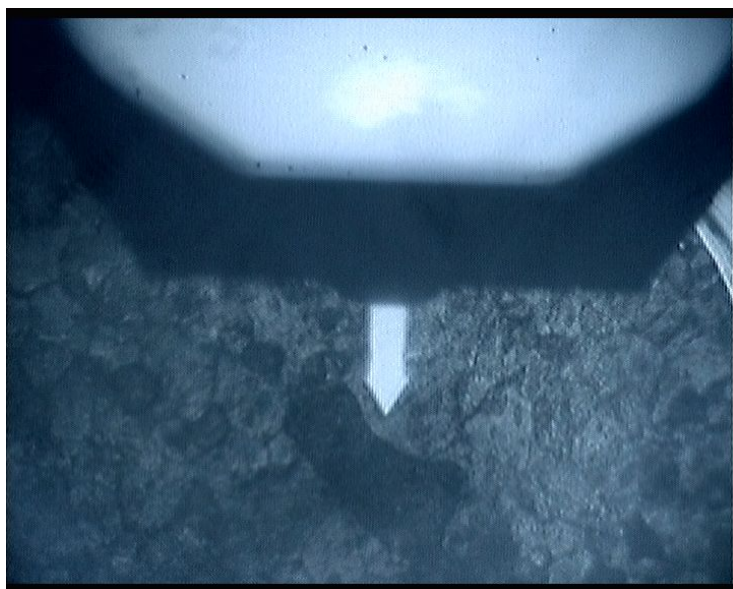
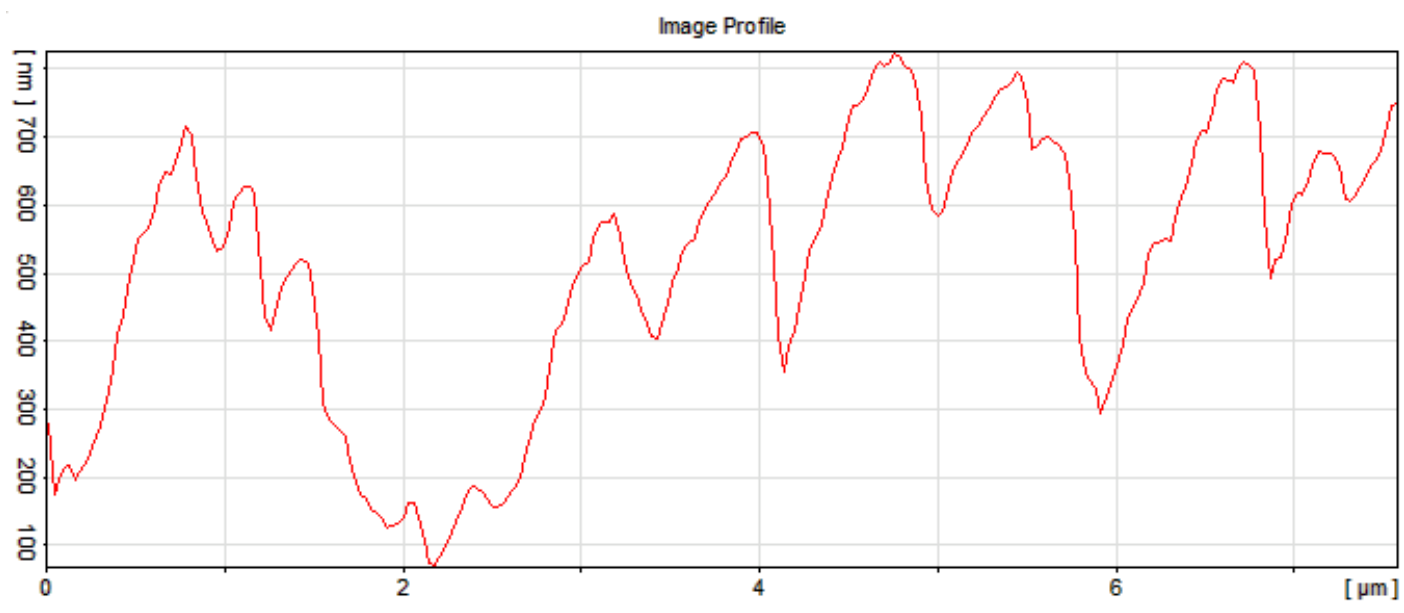
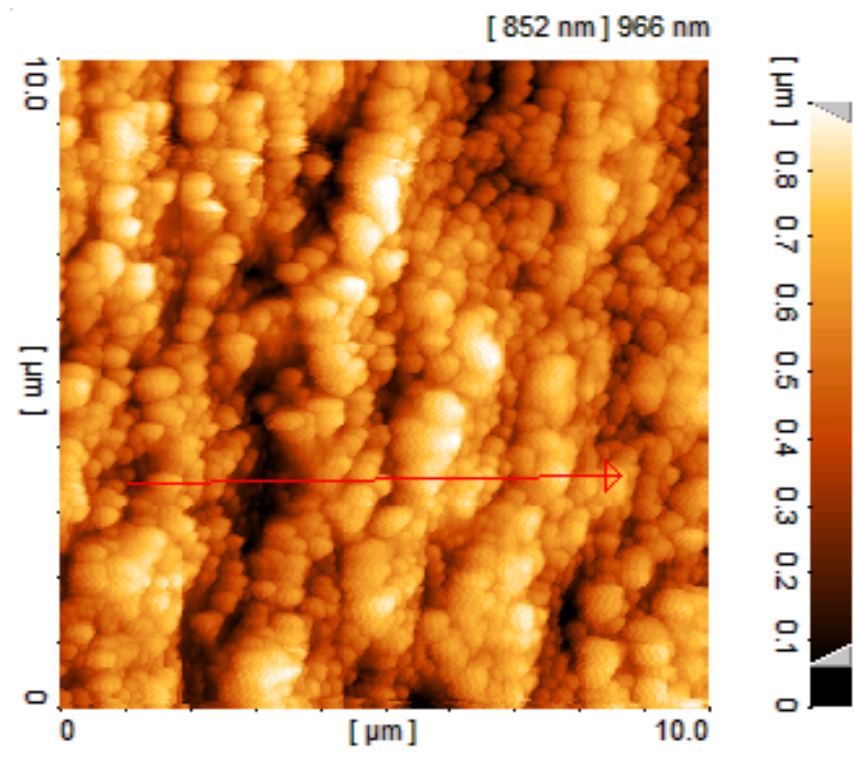


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.





EWEA AFM SAMPLES

L53 (260-301) RAE [L53-2]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

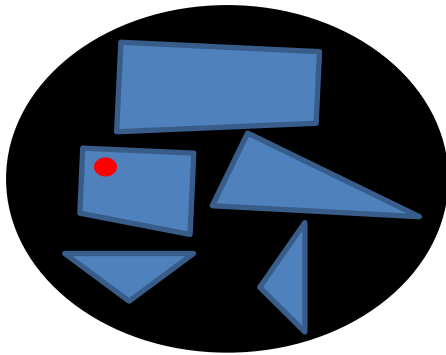
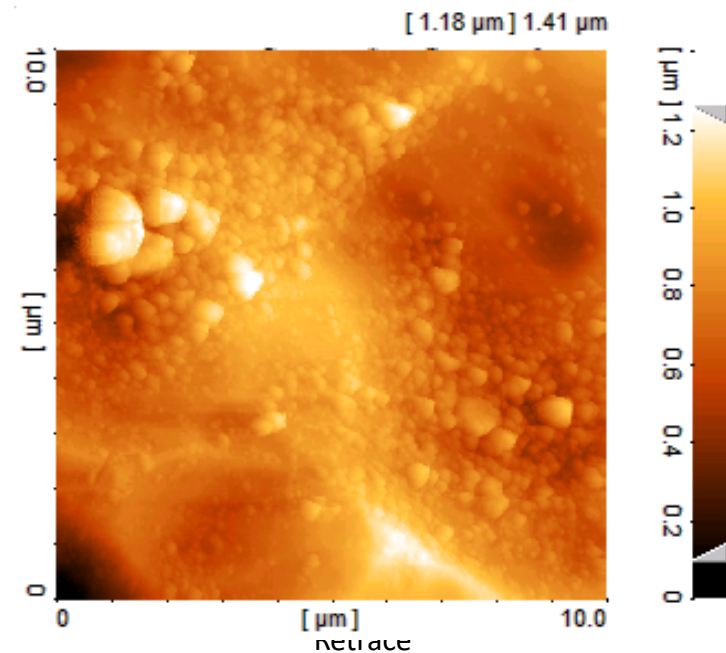
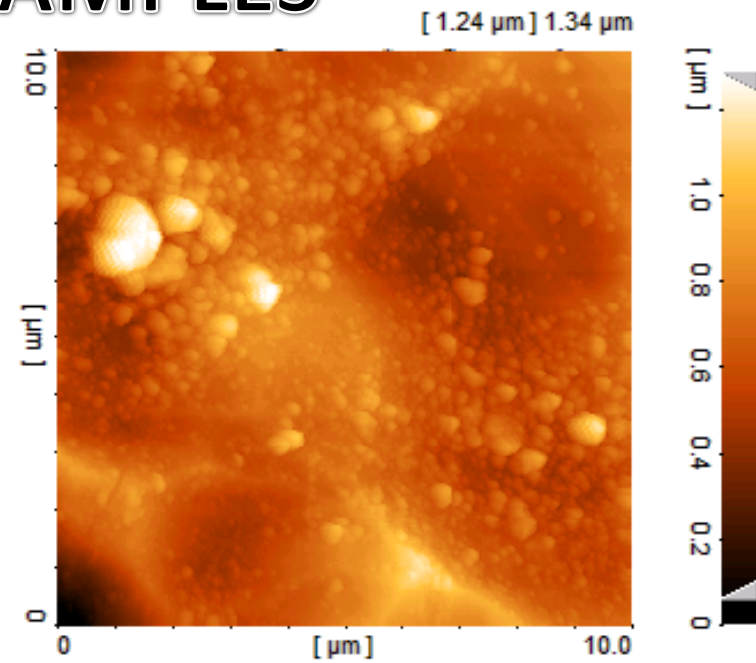
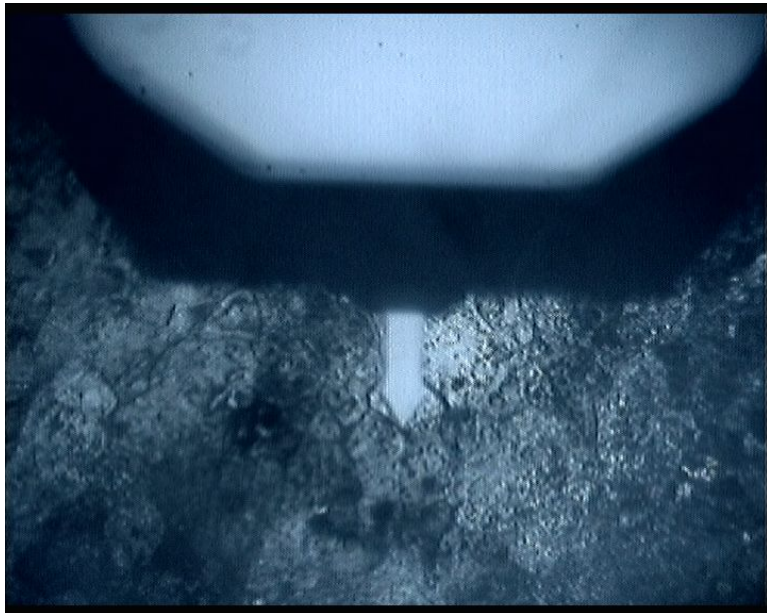
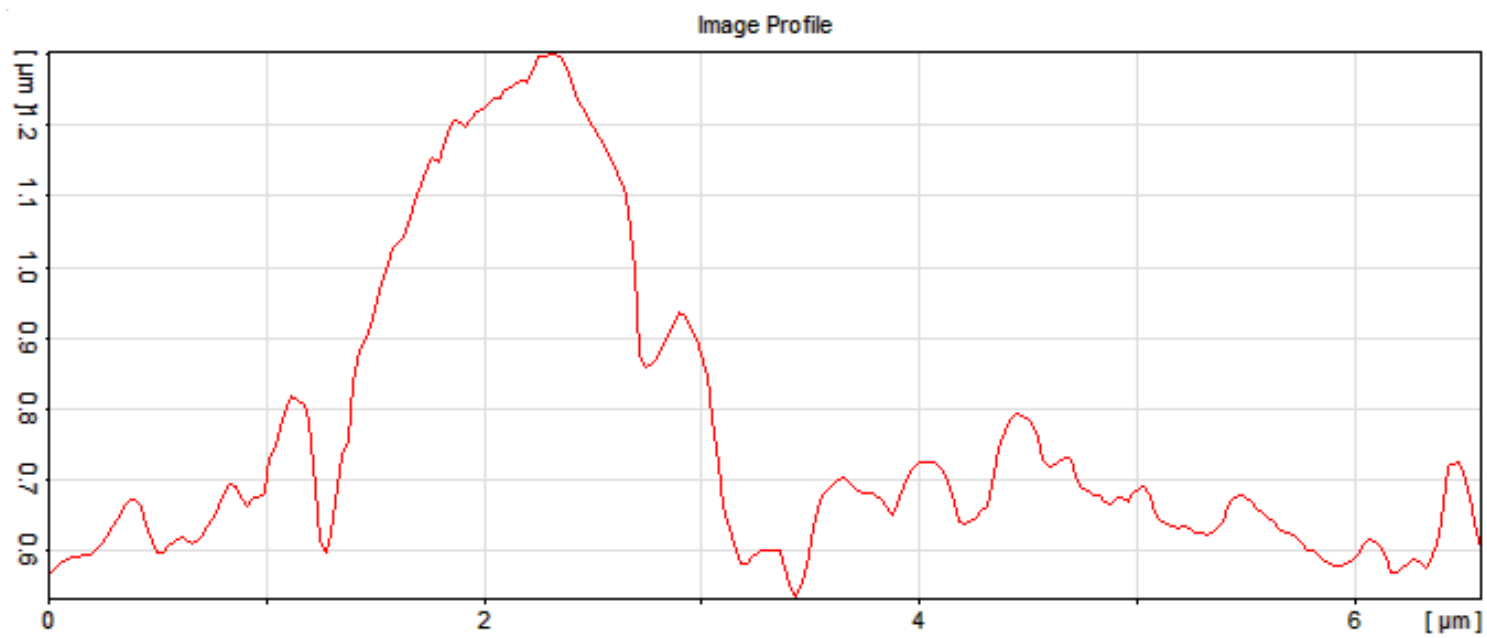
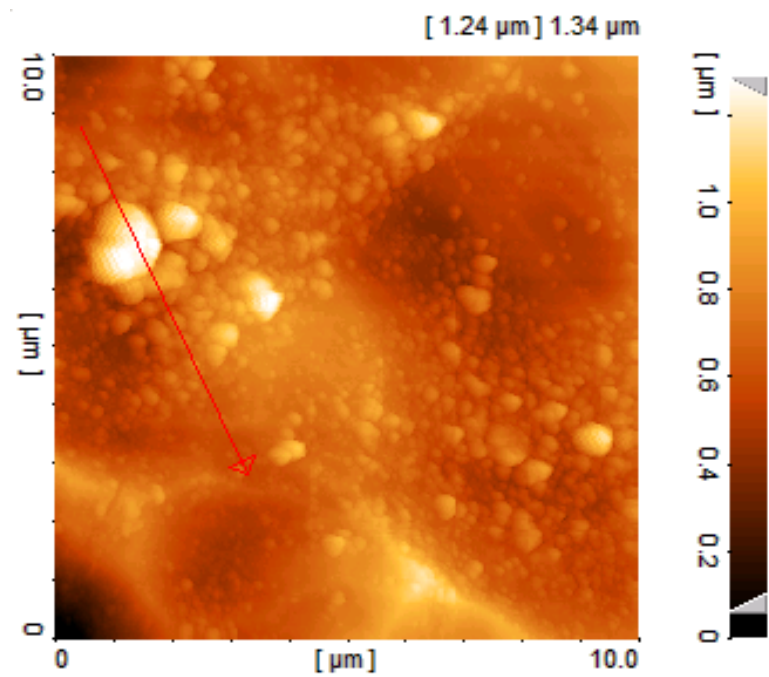


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.





EWEA AFM SAMPLES

L53 (260-301) RAE [L53-3]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

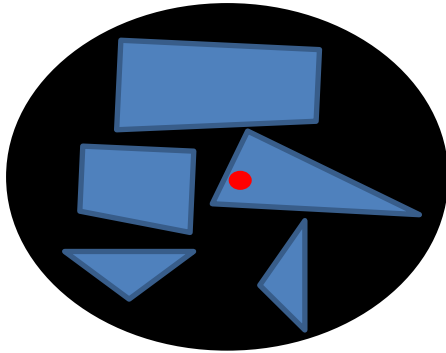
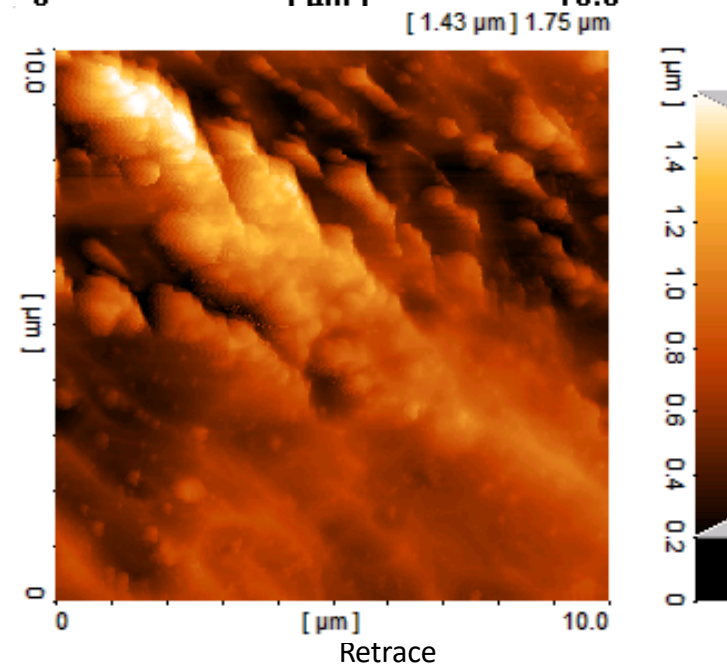
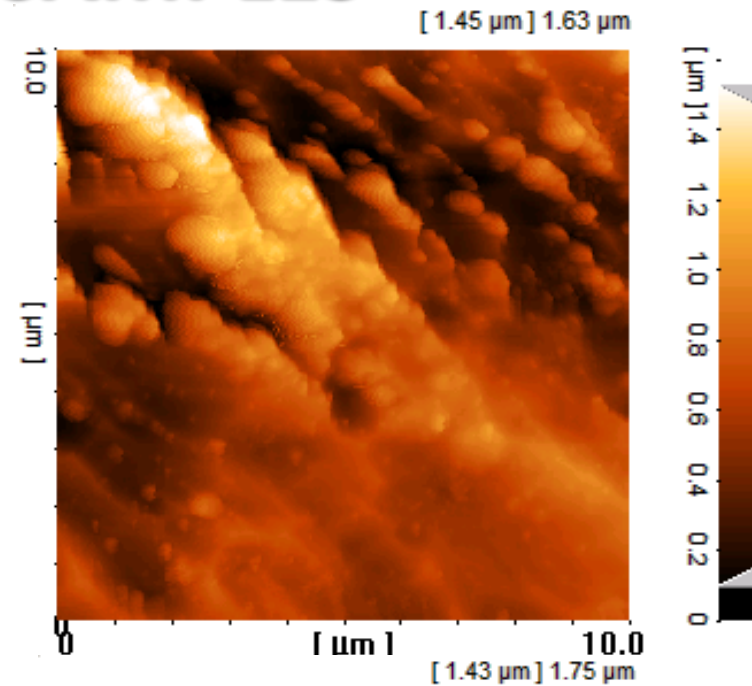
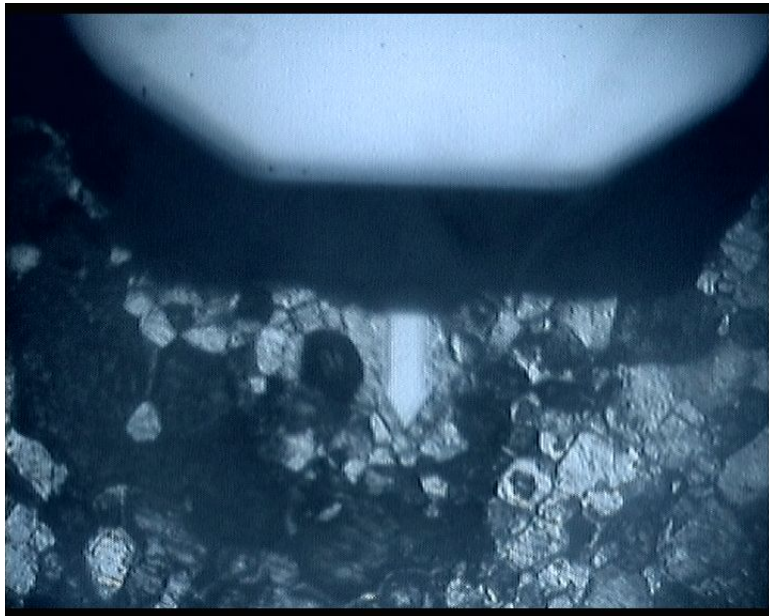
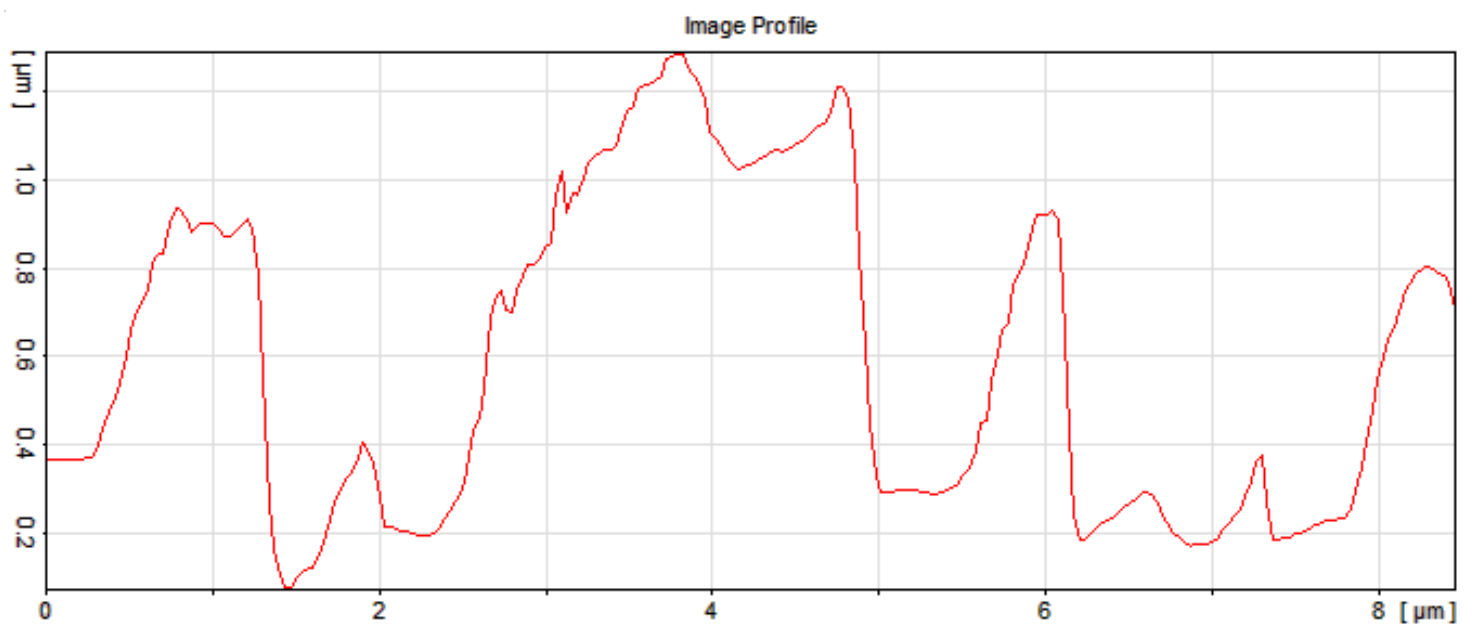
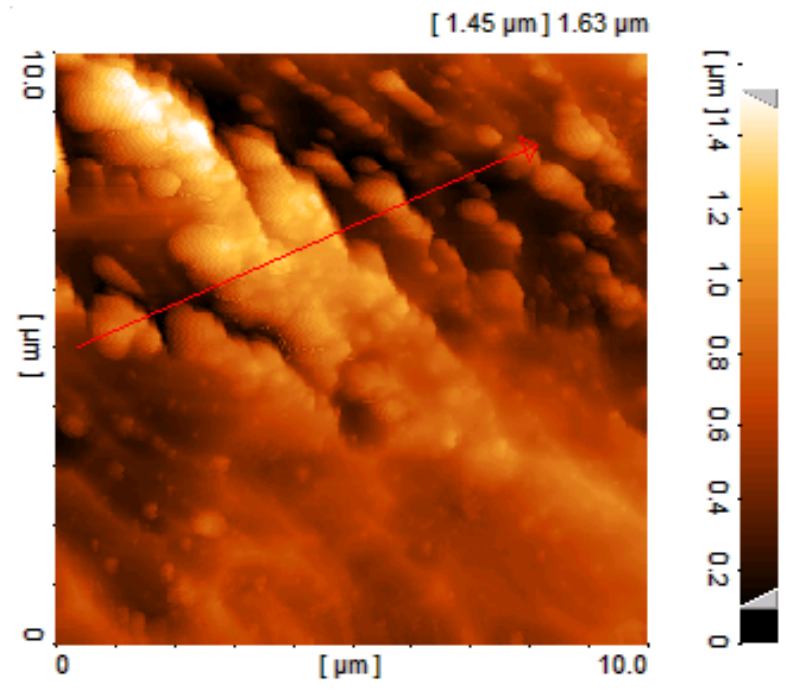


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.





EWEA AFM SAMPLES

L53 (260-301) RAE [L53-4]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

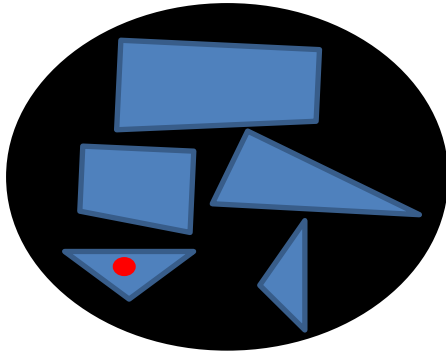
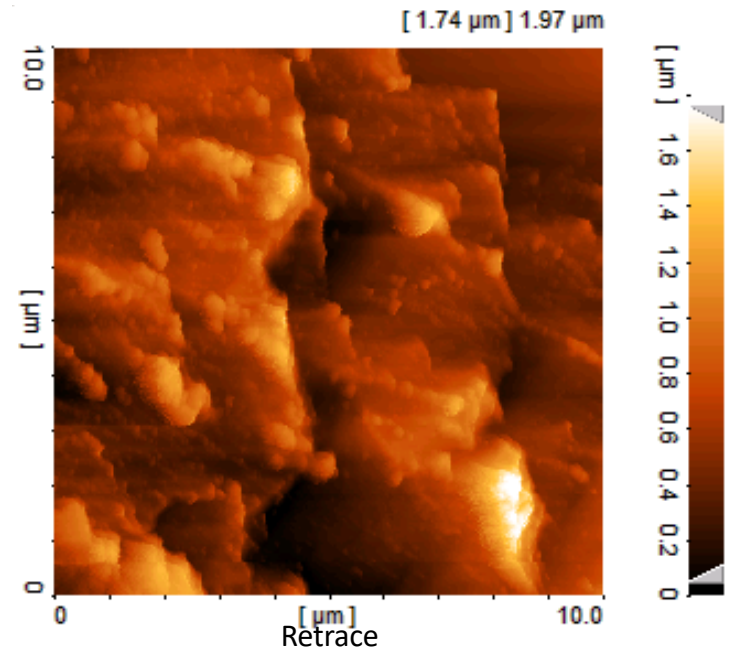
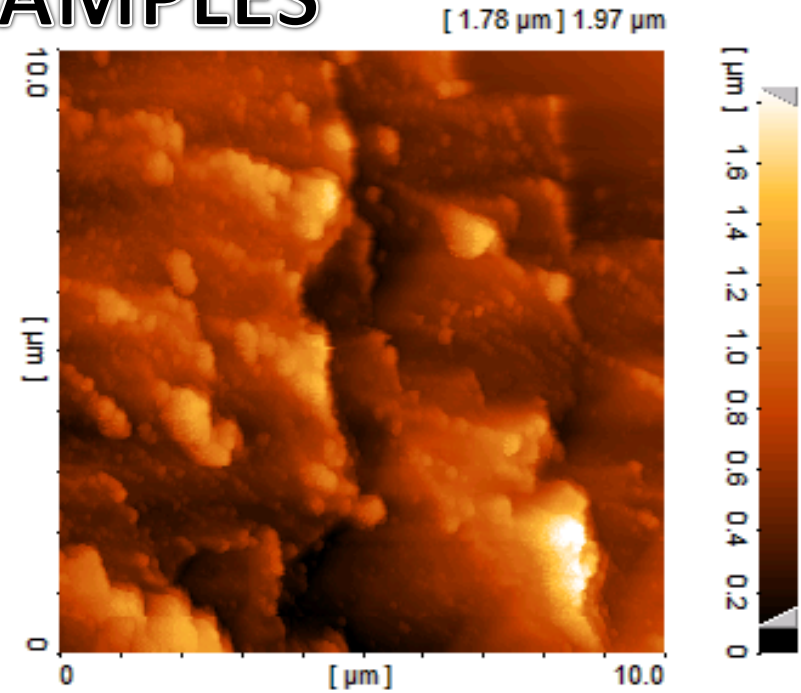
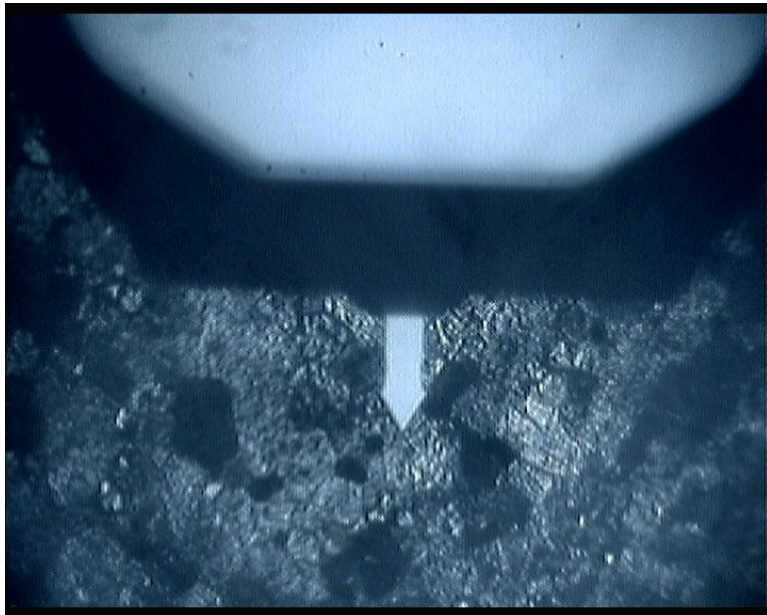


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.



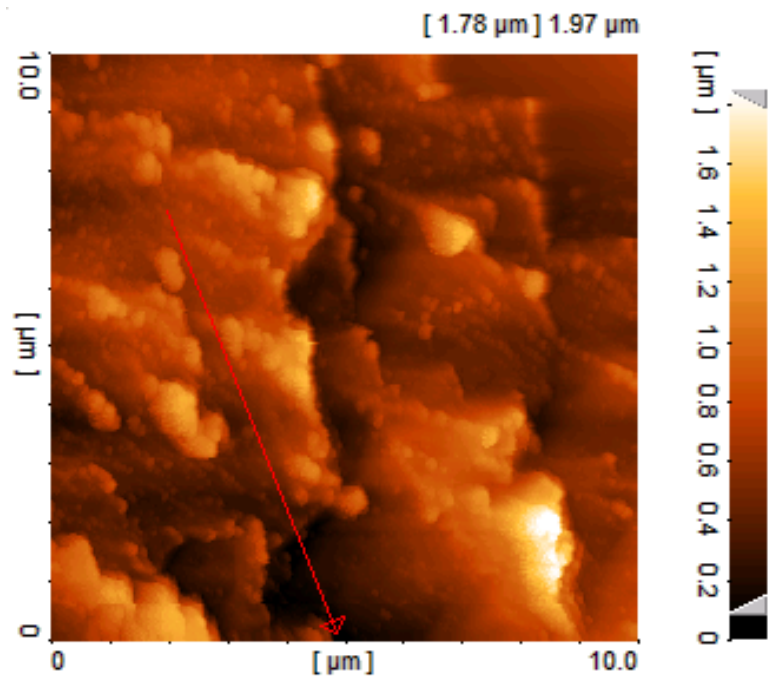
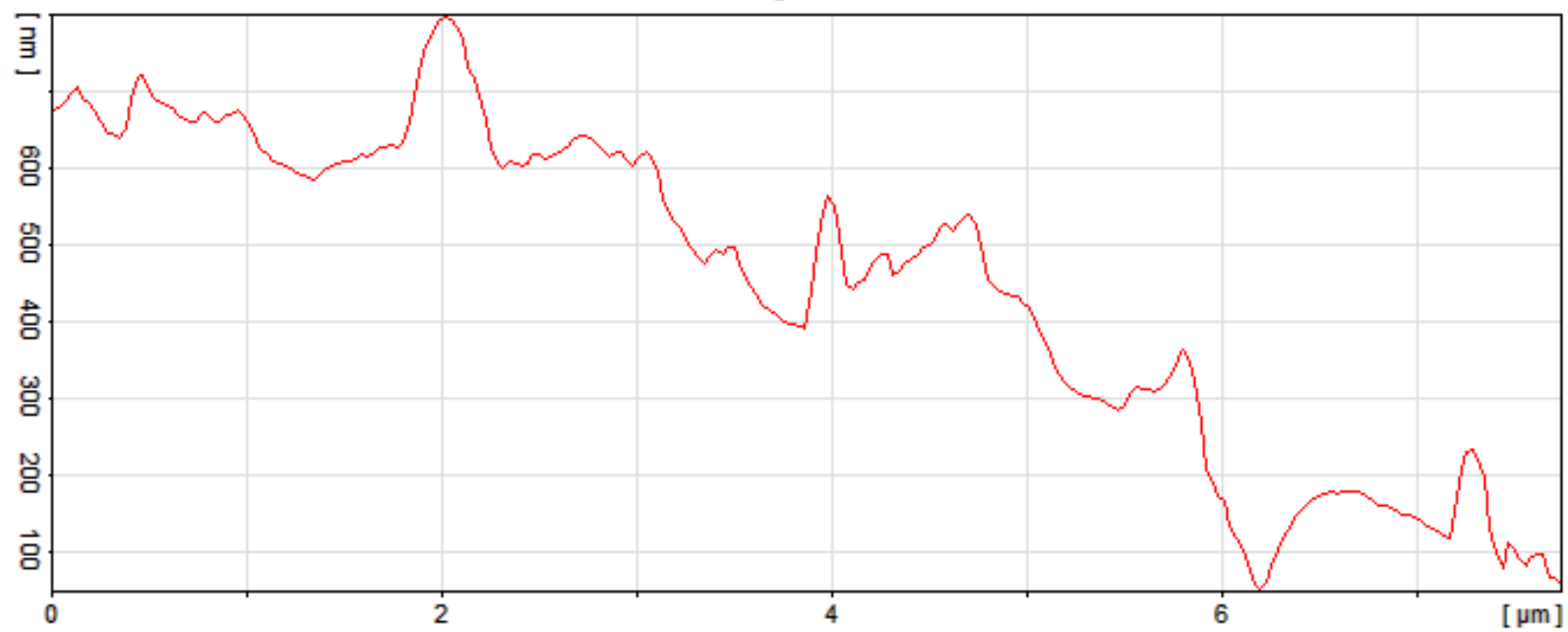


Image Profile



EWEA AFM SAMPLES

L53 (260-301) RAE [L53-5]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

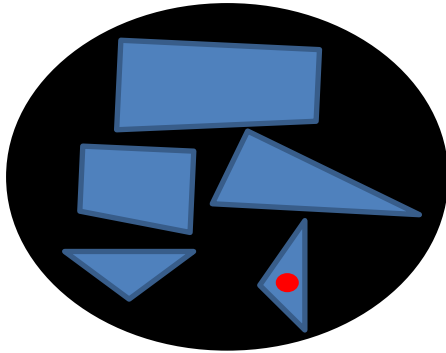
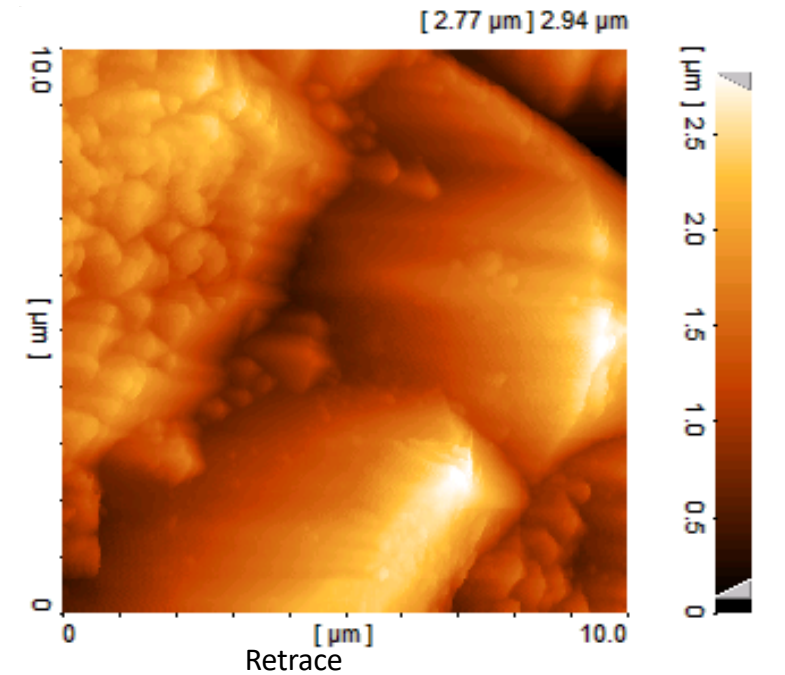
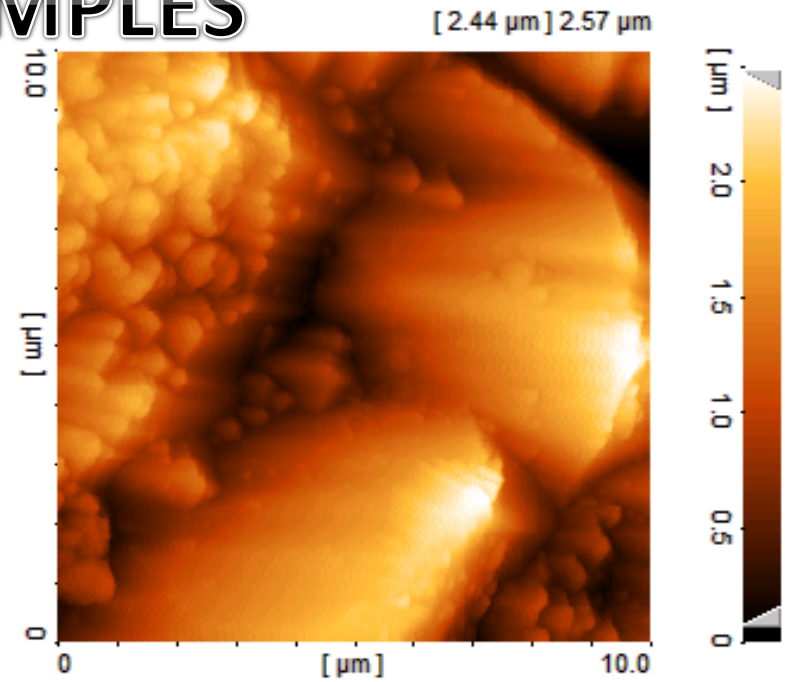
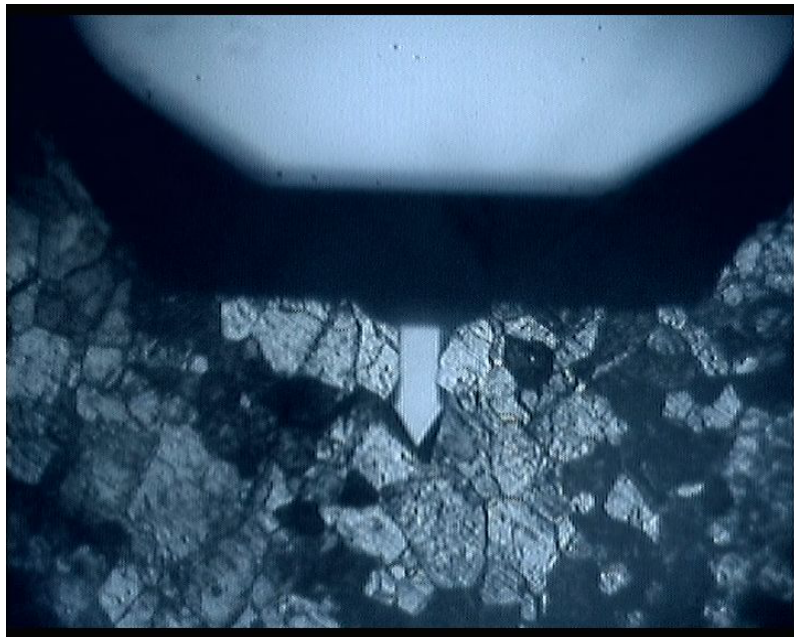
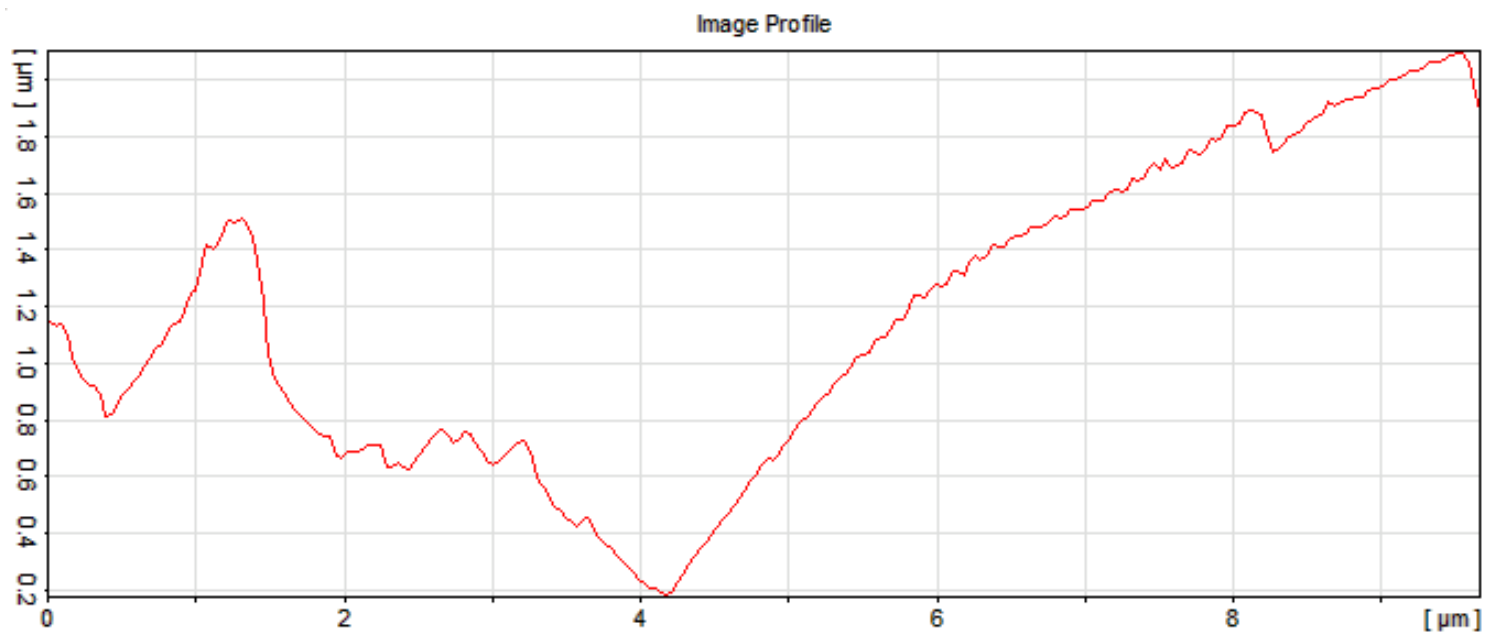
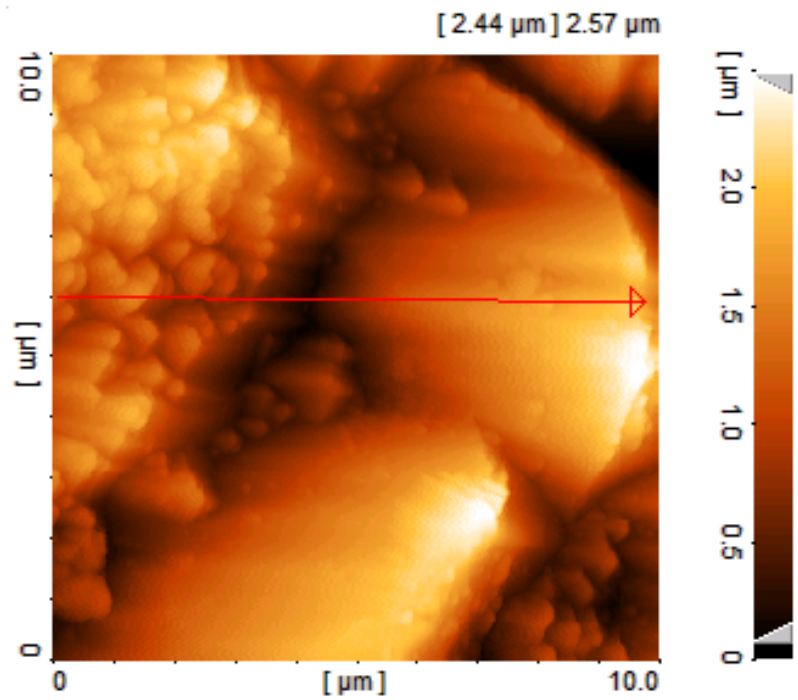


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.





EWEA AFM SAMPLES

L5 [L5-1]

128 pixels

20 μ m \times 20 μ m

Image was taken with a standard Silicon Tip.

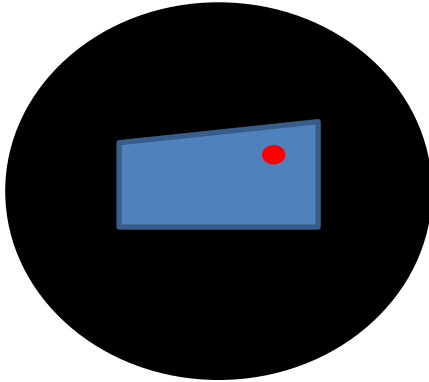
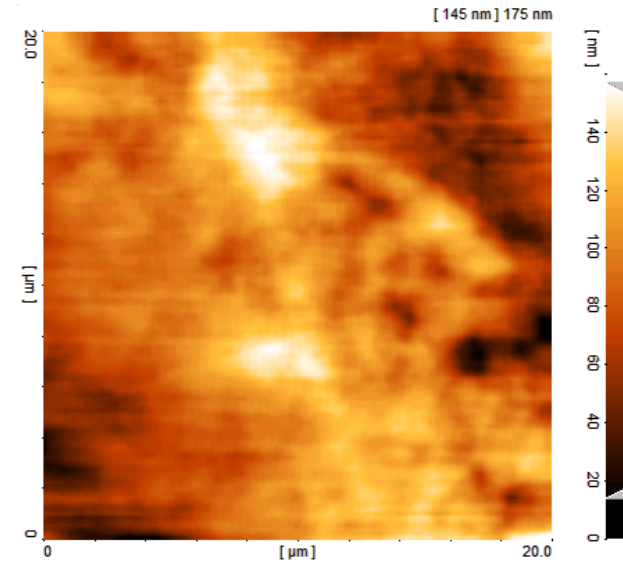
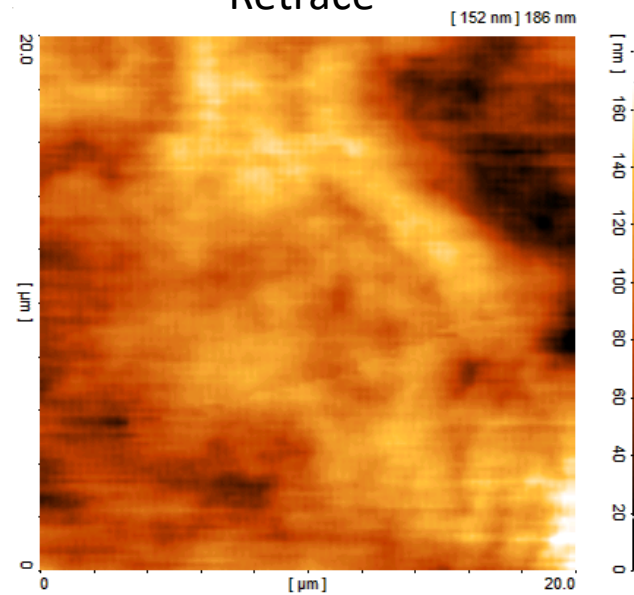


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.



Retrace



EWEA AFM SAMPLES

L5 [L5-2]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

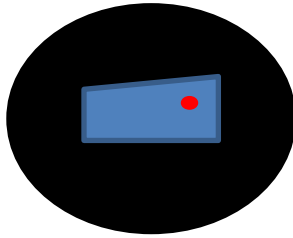
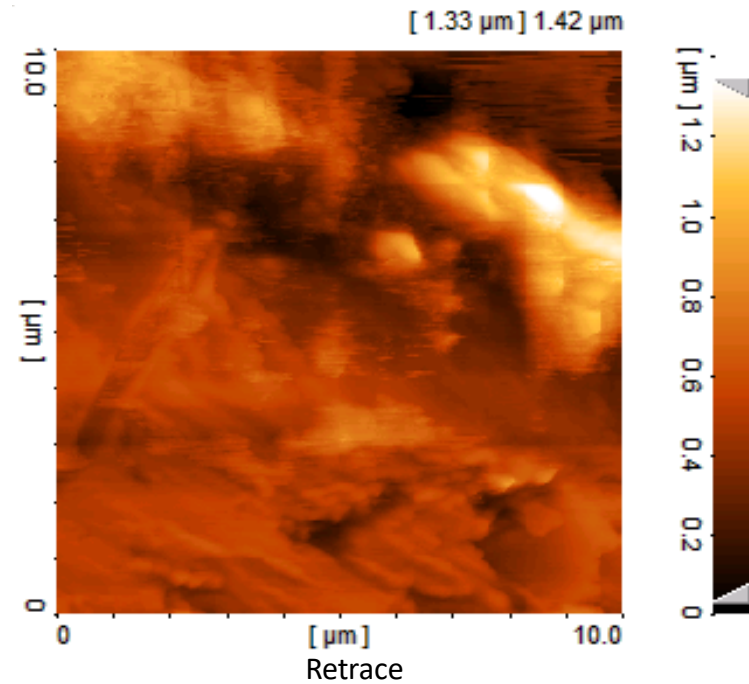
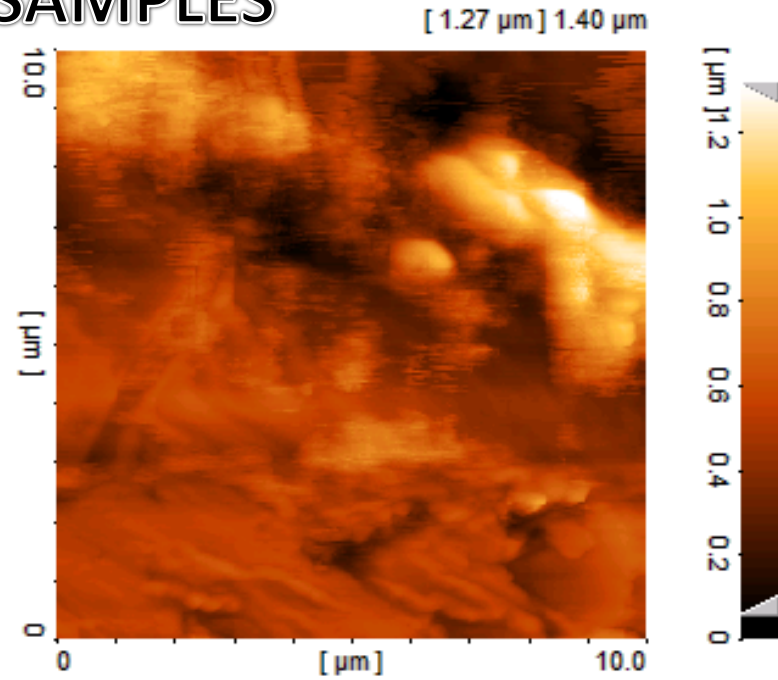
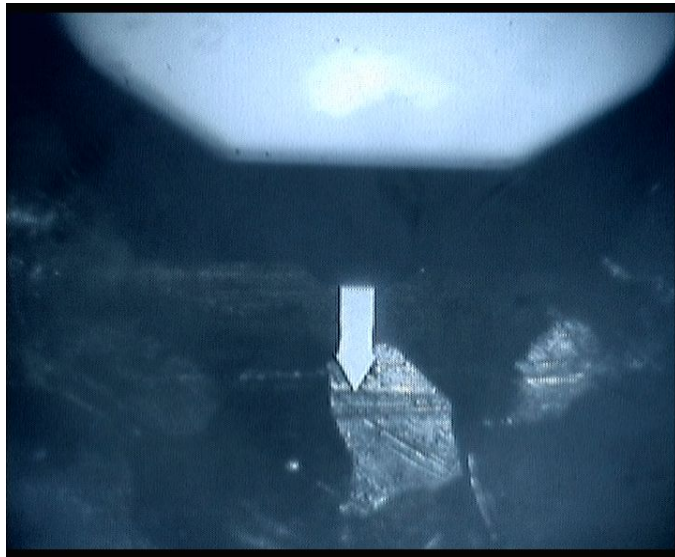
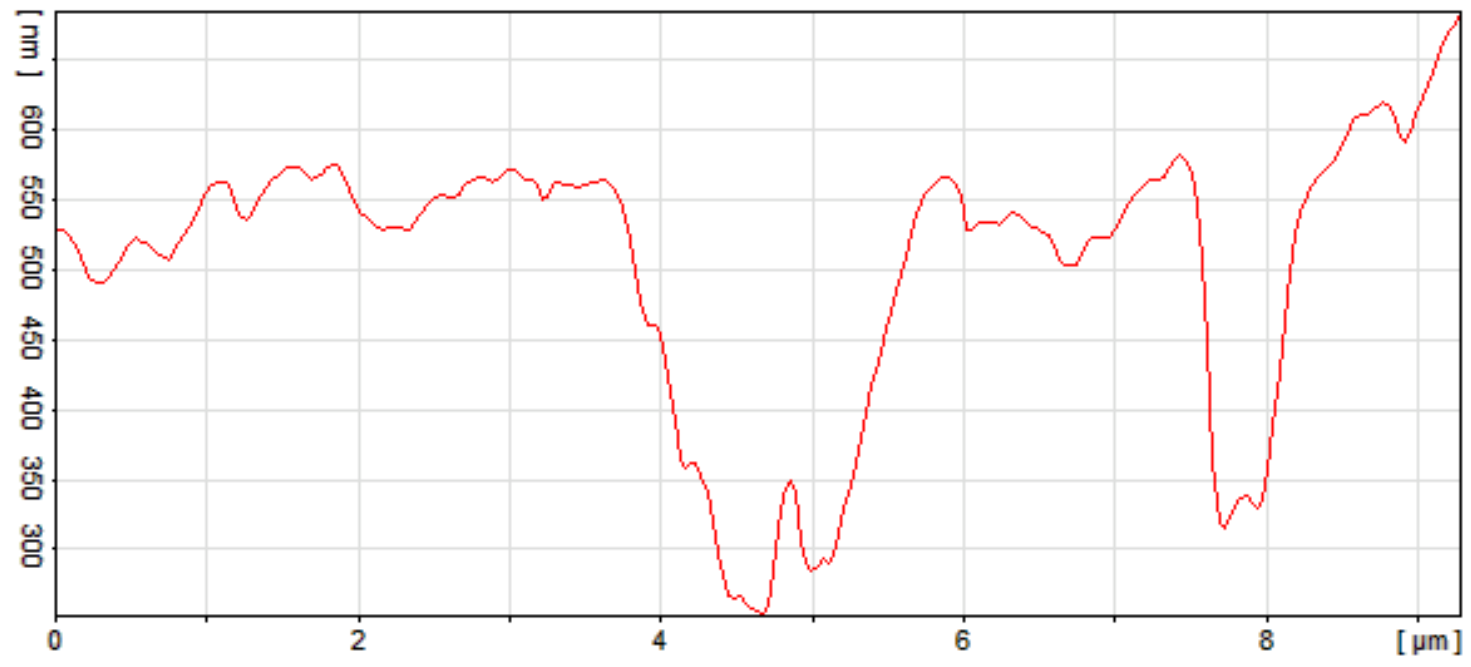
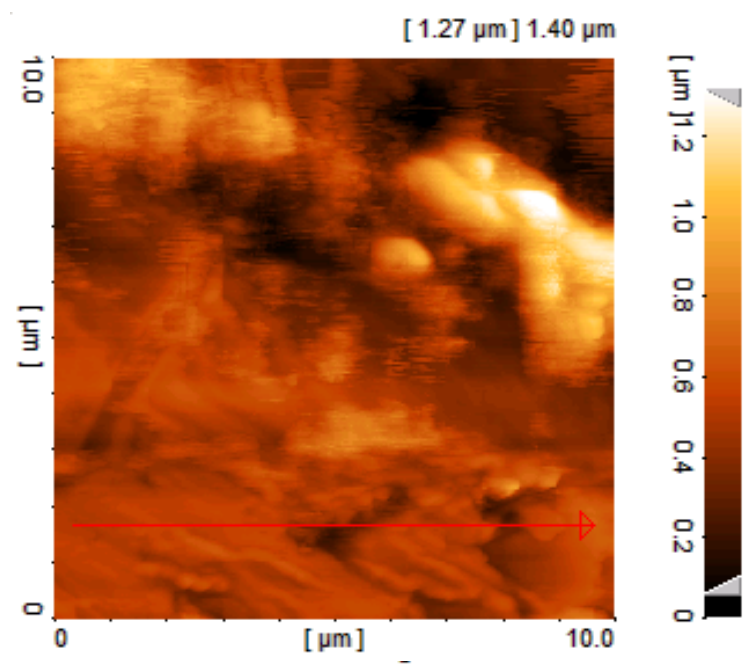


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.





EWEA AFM SAMPLES

L5 [L5-3]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

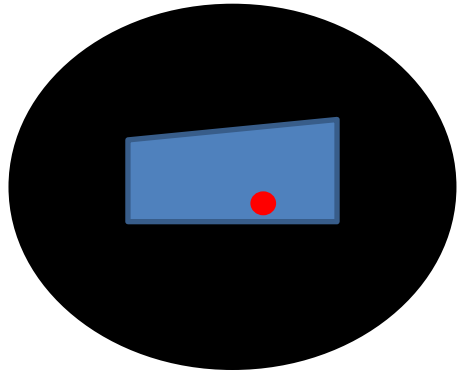
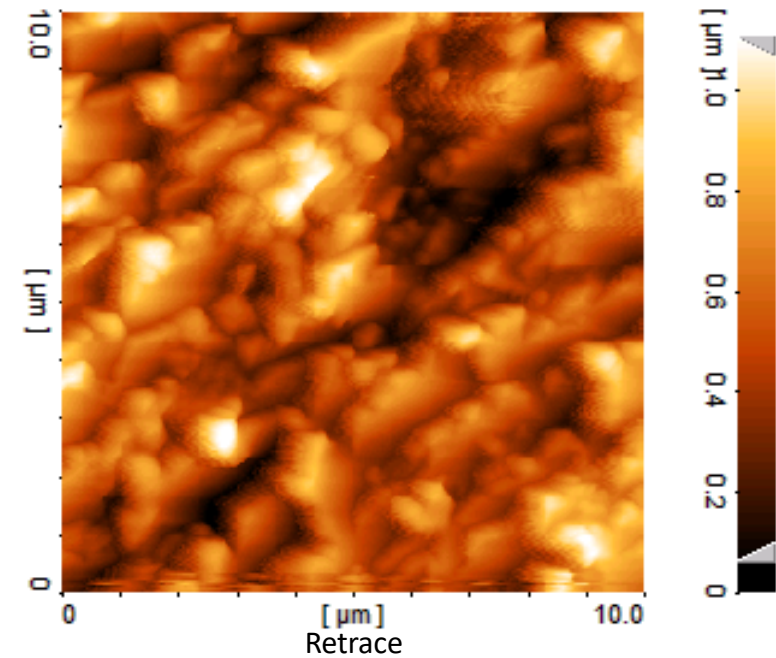
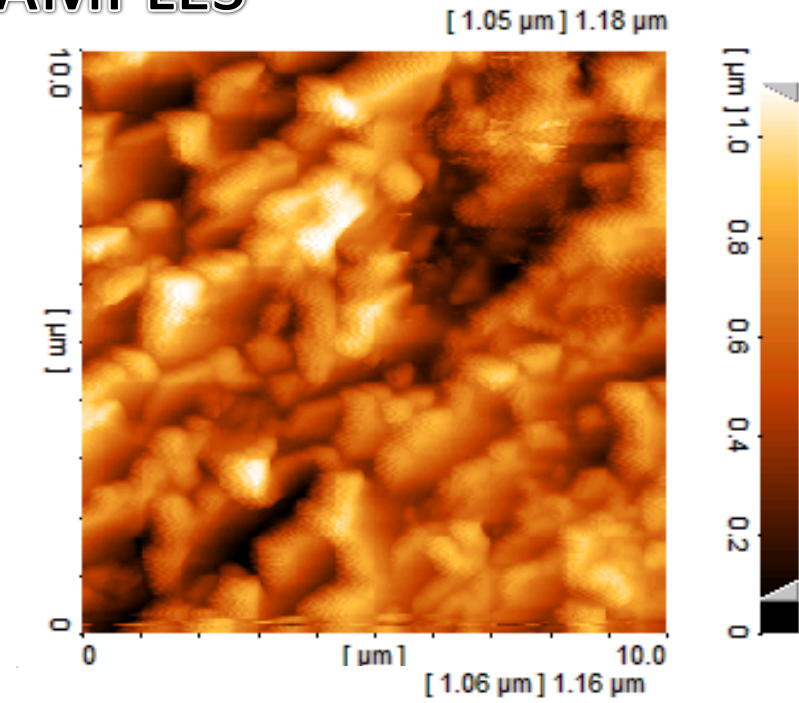


Diagram of sample on SEM stub
Red Circle indicates region of image taken by AFM.



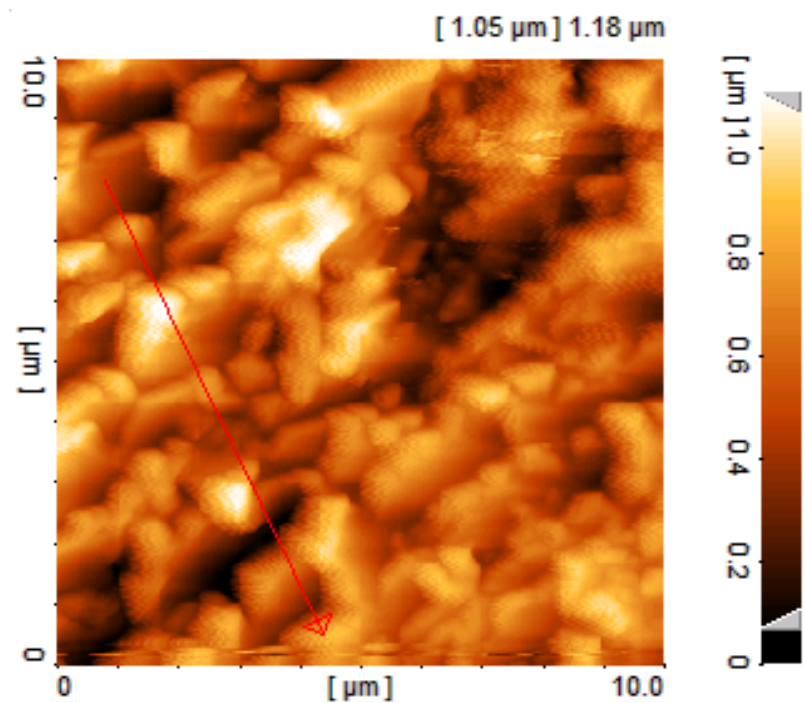
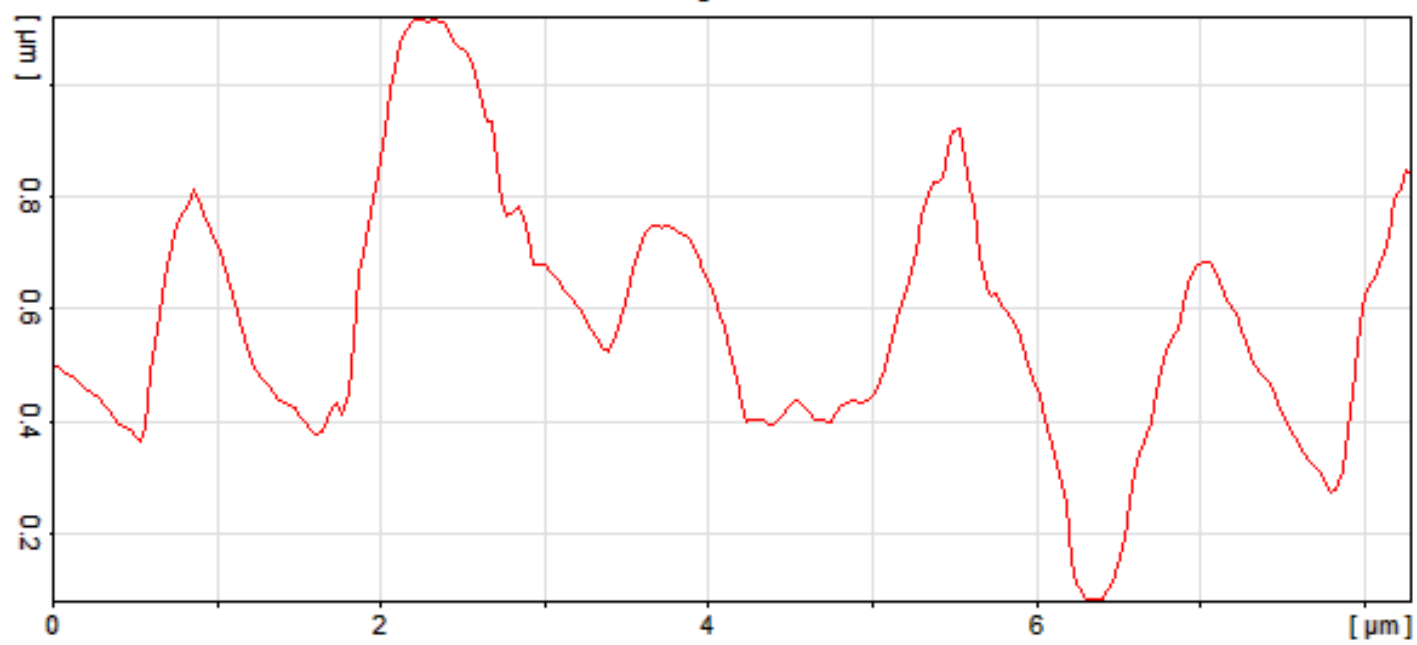


Image Profile



EWEA AFM SAMPLES

L5 [L5-4]

256 pixels

15 μ m \times 15 μ m

Image was taken with a standard Silicon Tip.

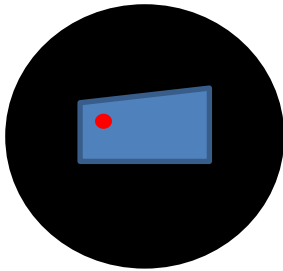
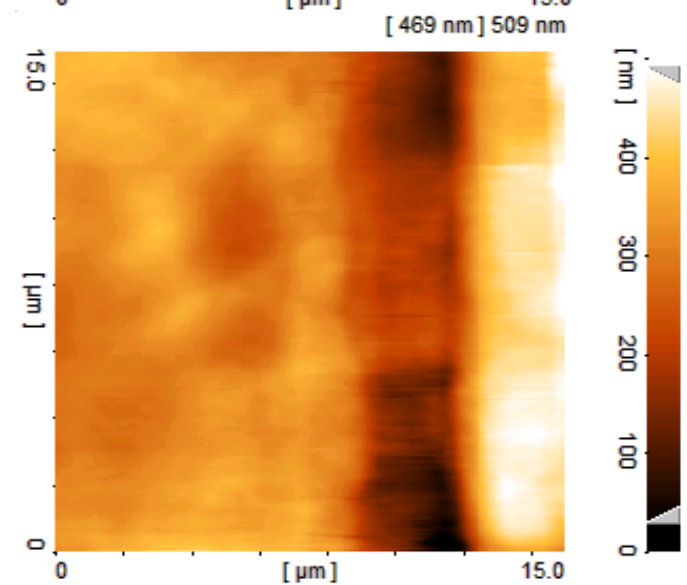
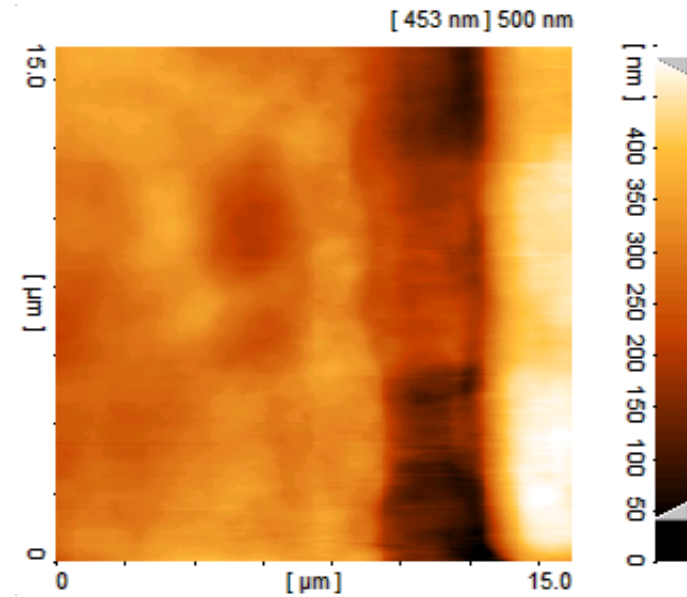
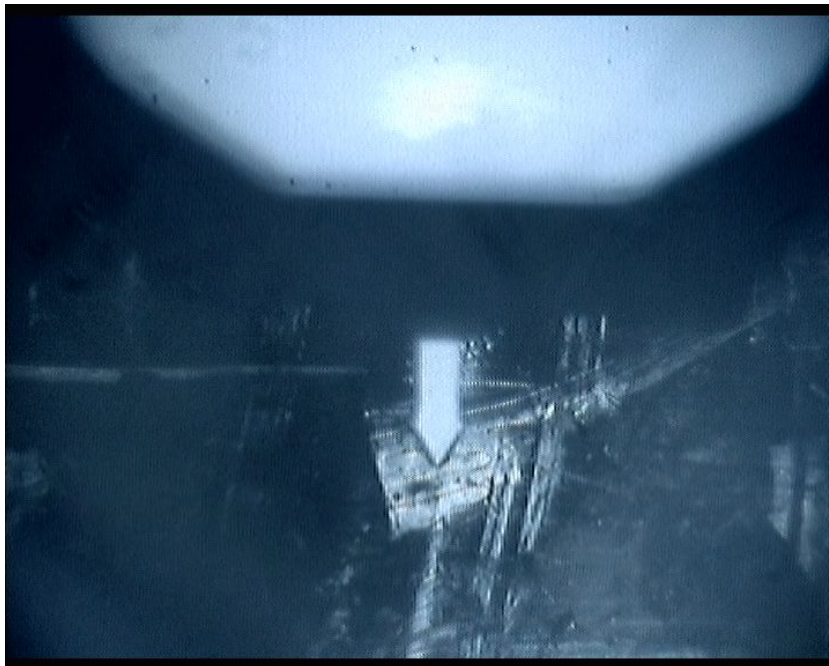
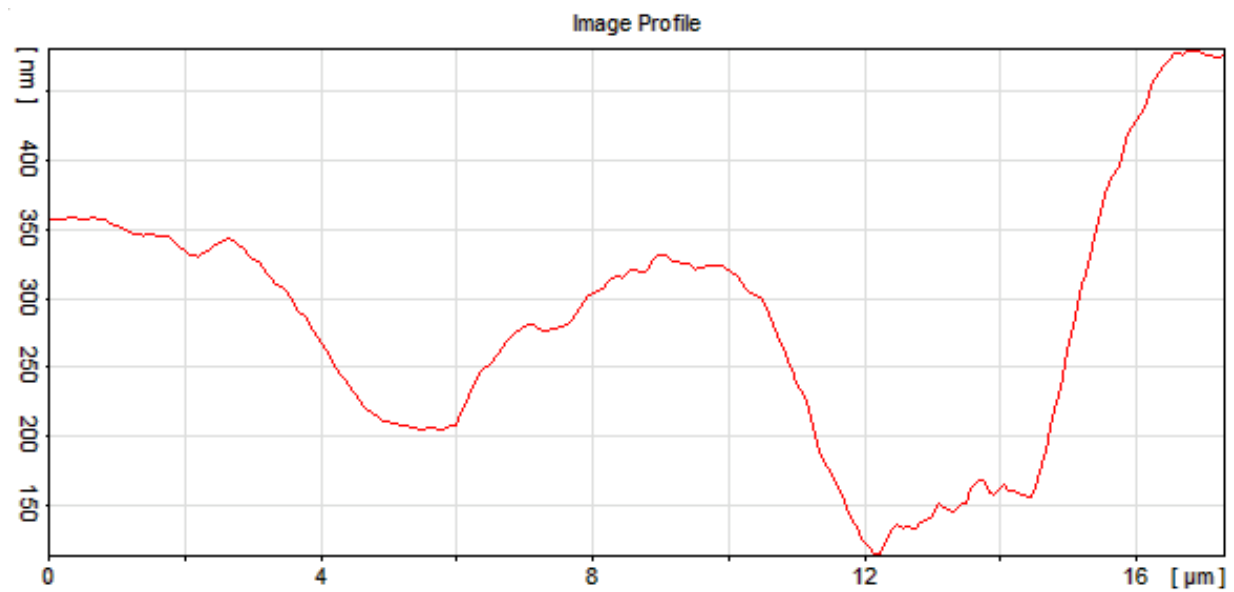
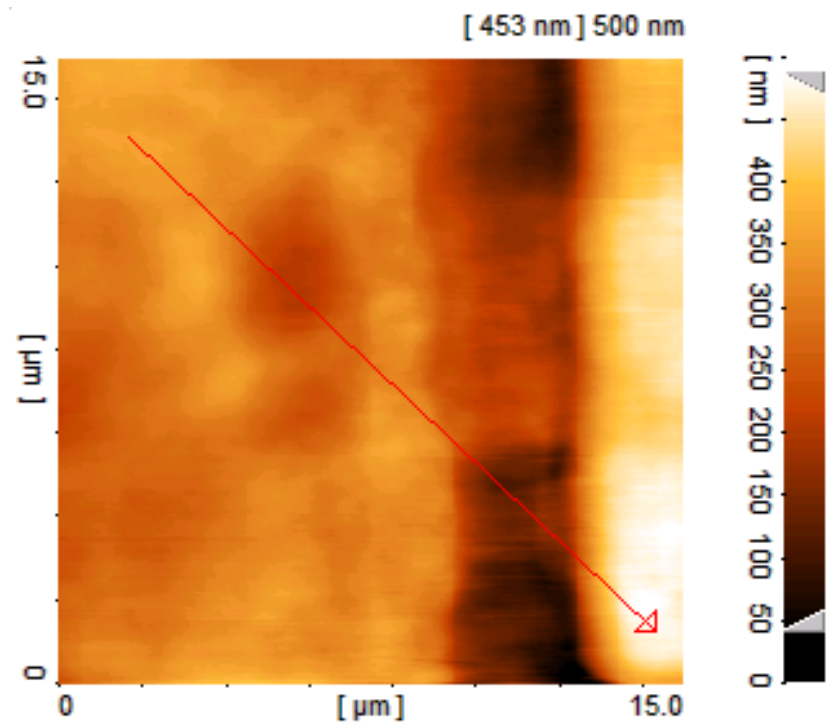


Diagram of sample on SEM stub
Red Circle indicates region of image taken by AFM.



Retrace



EWEA AFM SAMPLES

L5 [L5-5]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

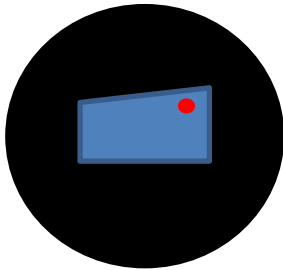
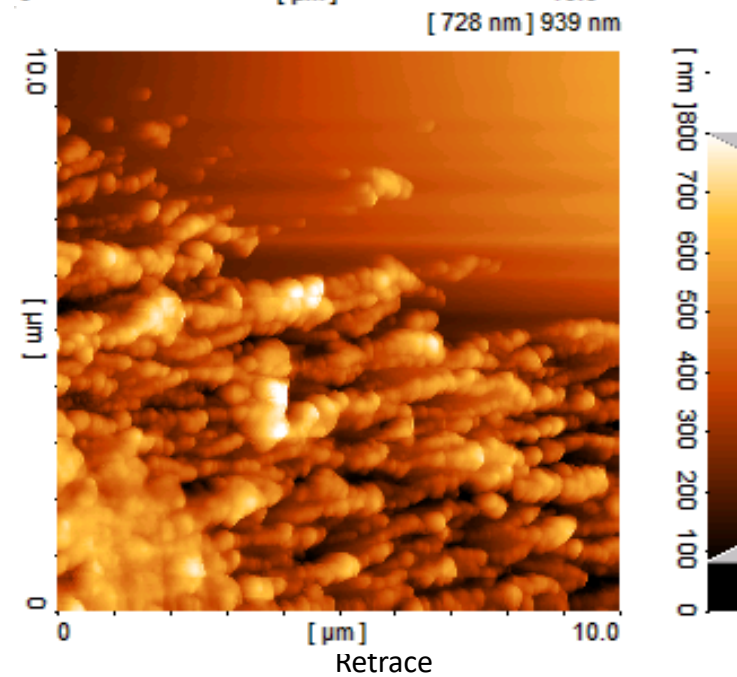
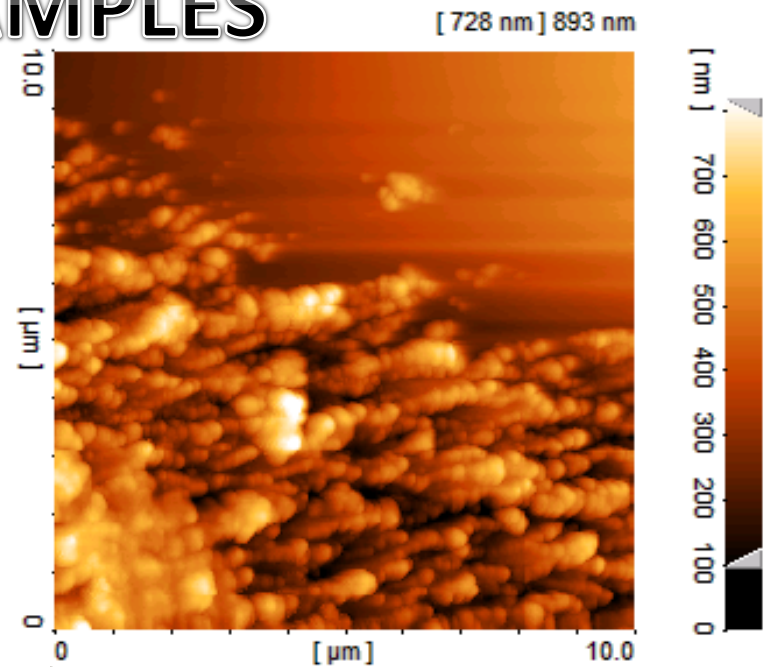
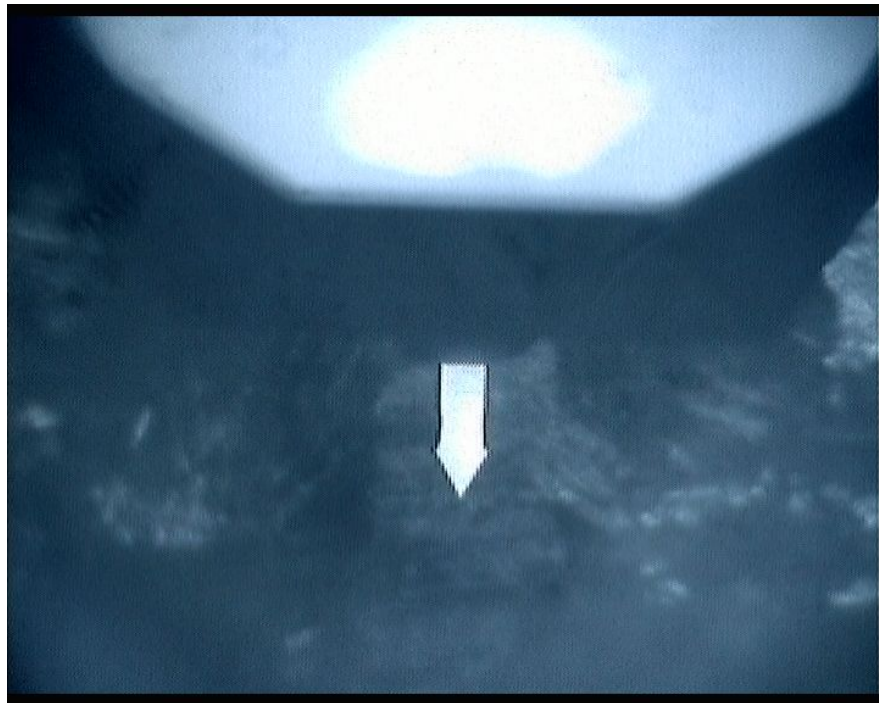
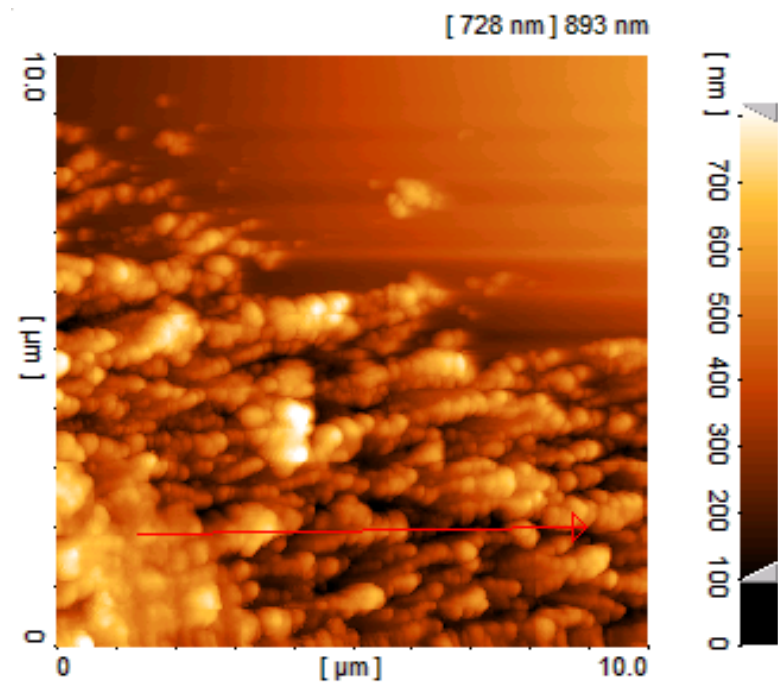


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.





EWEA AFM SAMPLES

L5 [L5-6]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

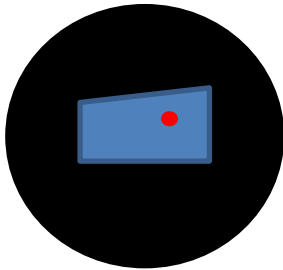
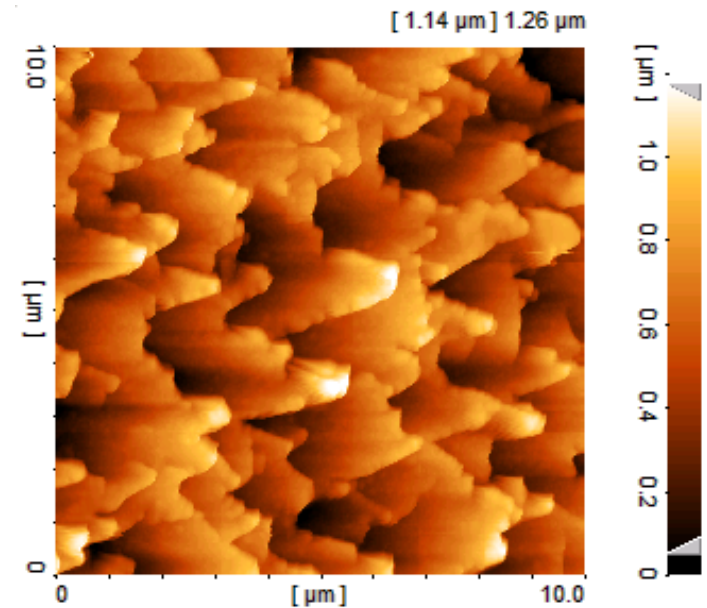
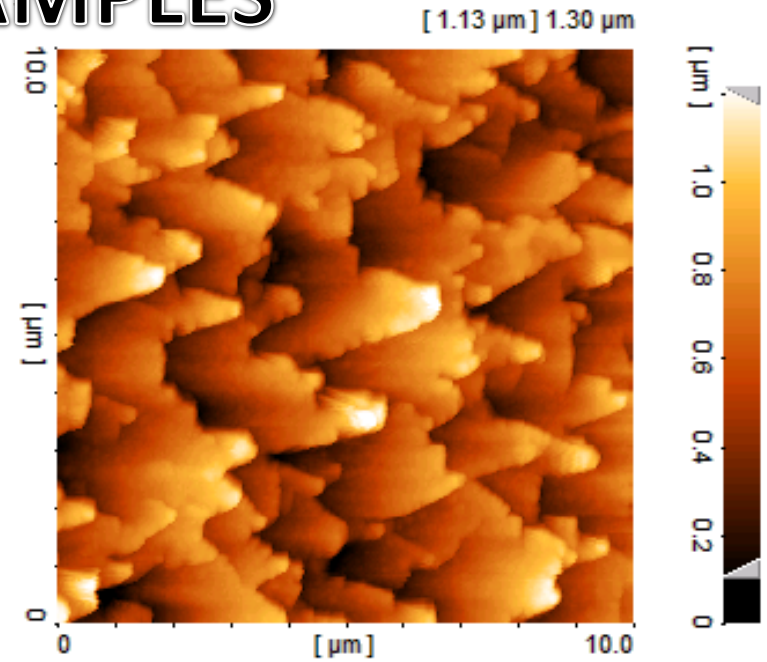


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.



Retrace

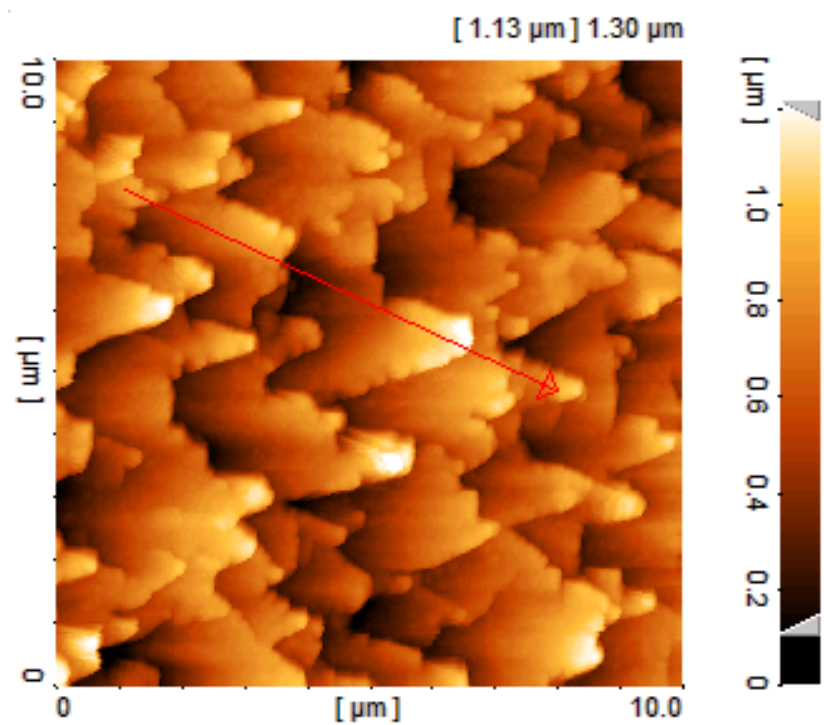
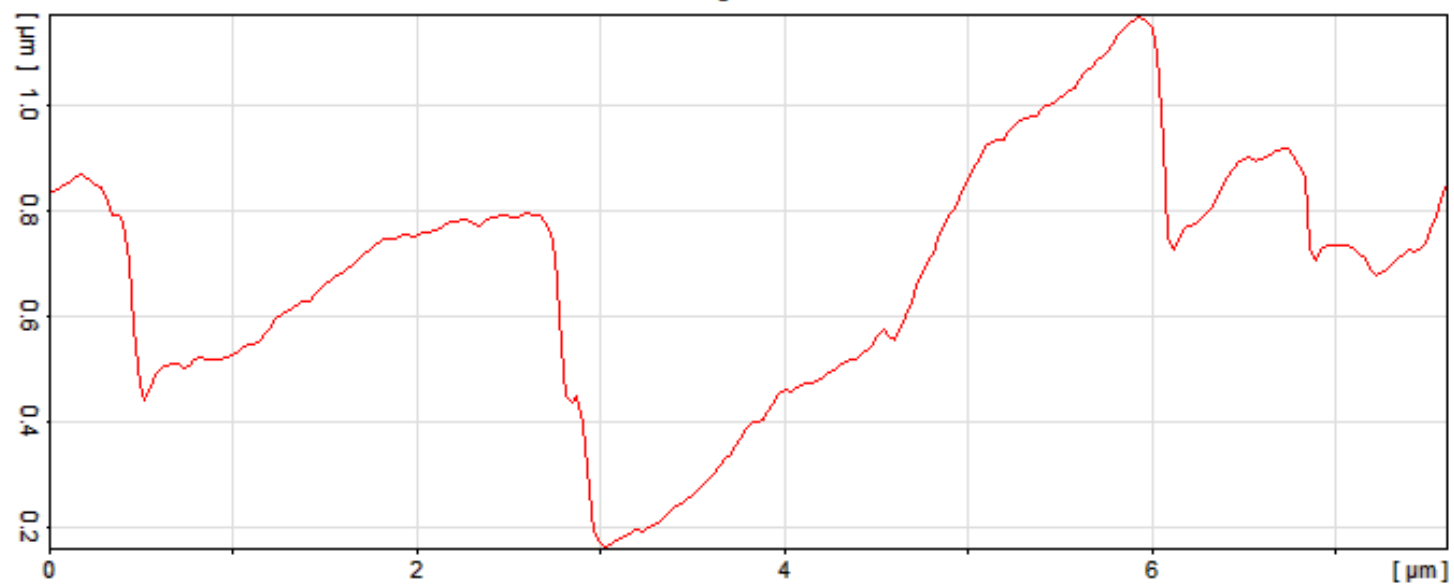


Image Profile



EWEA AFM SAMPLES

L5 [L5-7]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

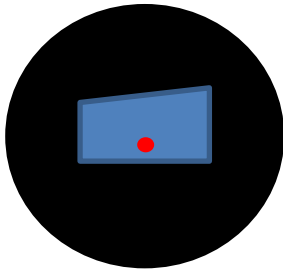
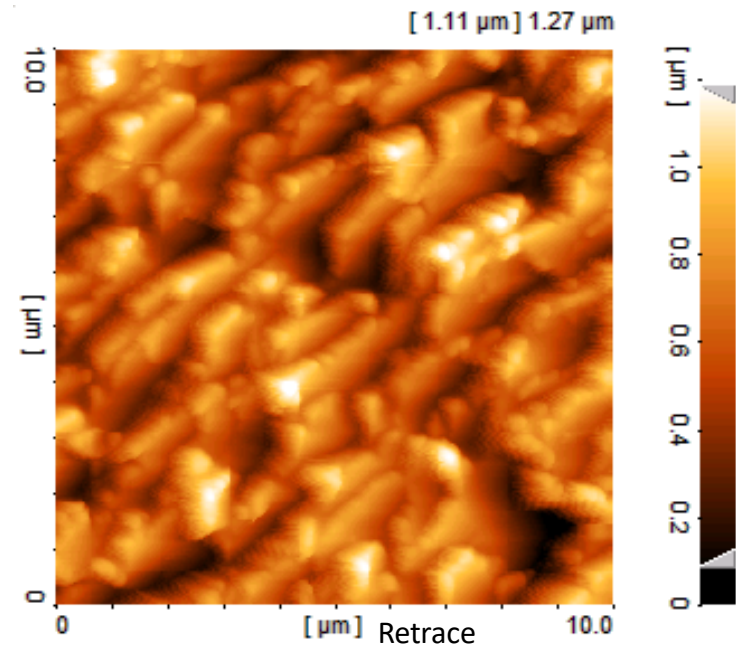
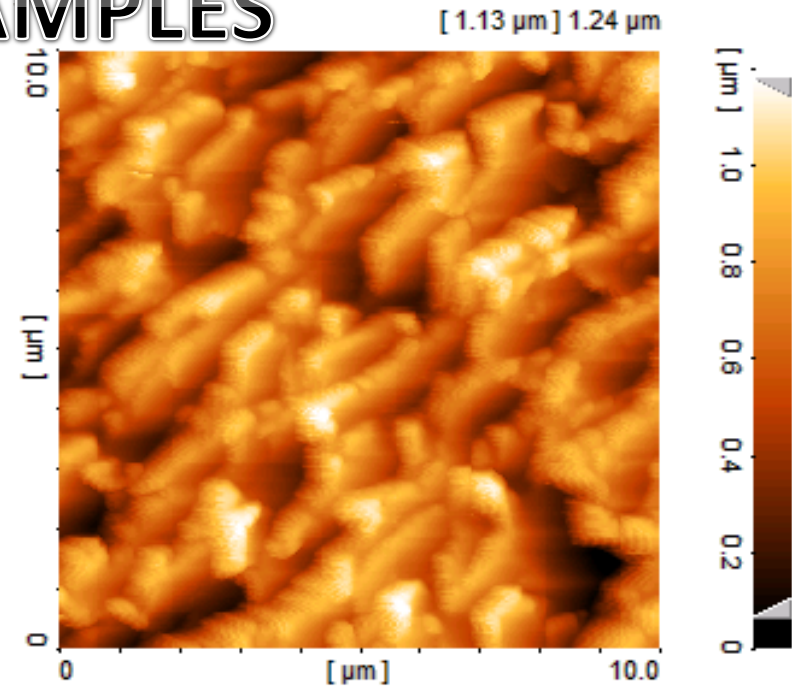
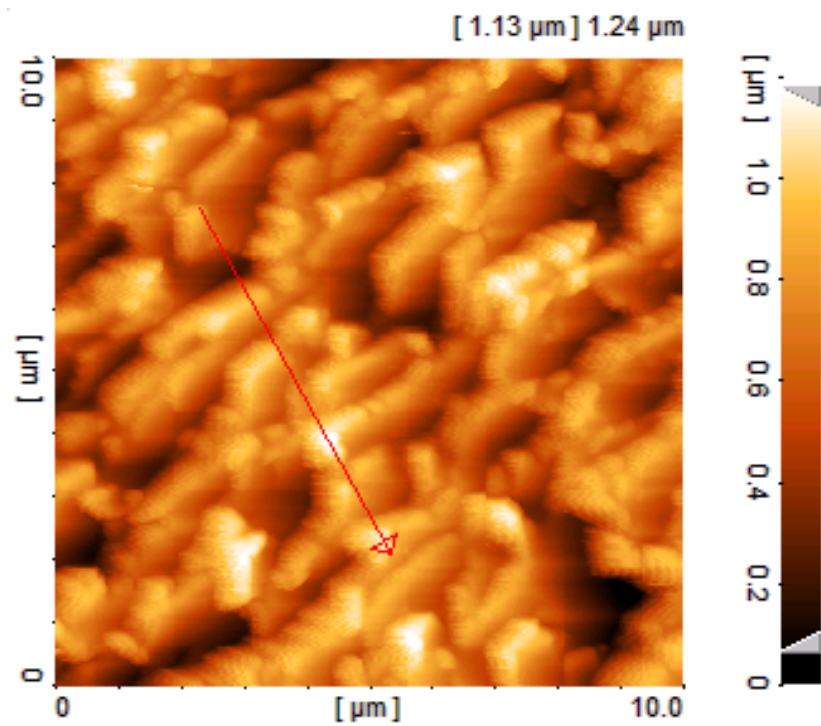


Diagram of sample on SEM stub
Red Circle indicates region of image taken by AFM.





EWEA AFM SAMPLES

L5 [L5-8]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

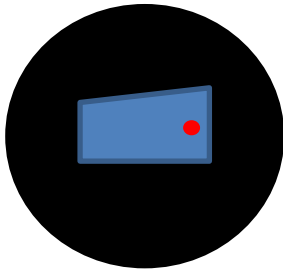
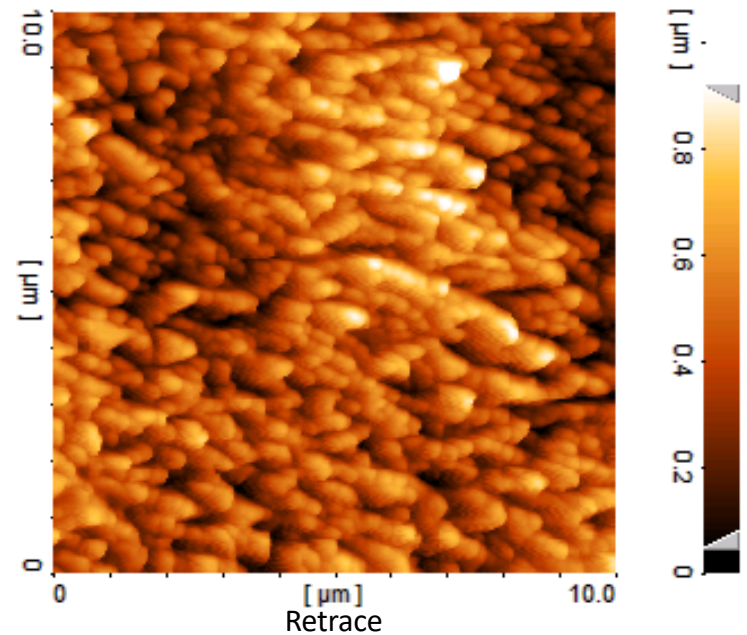
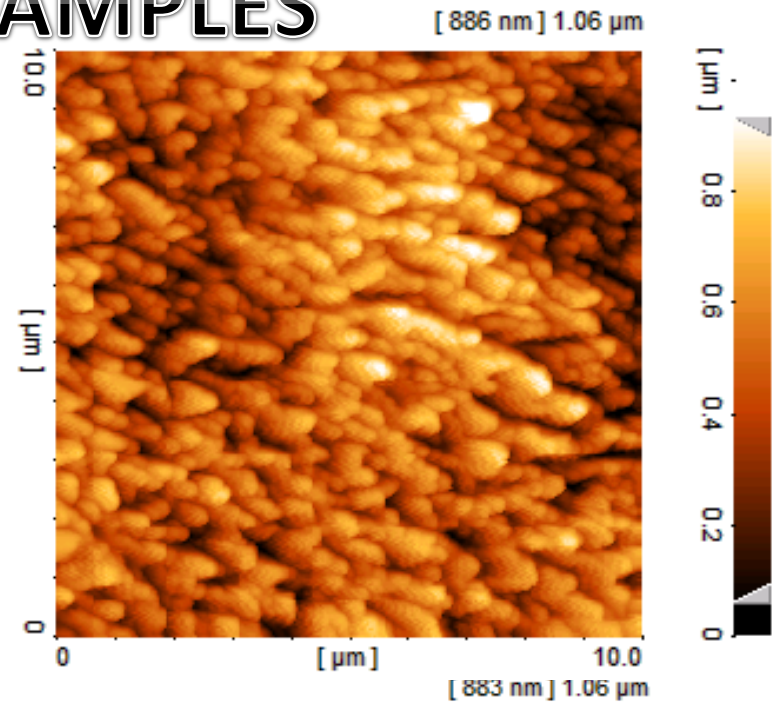
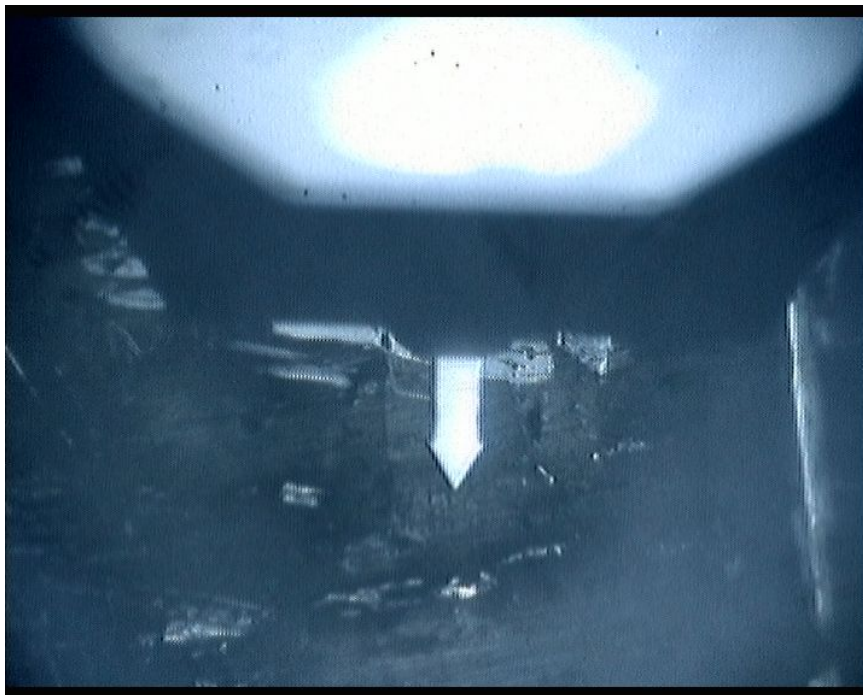
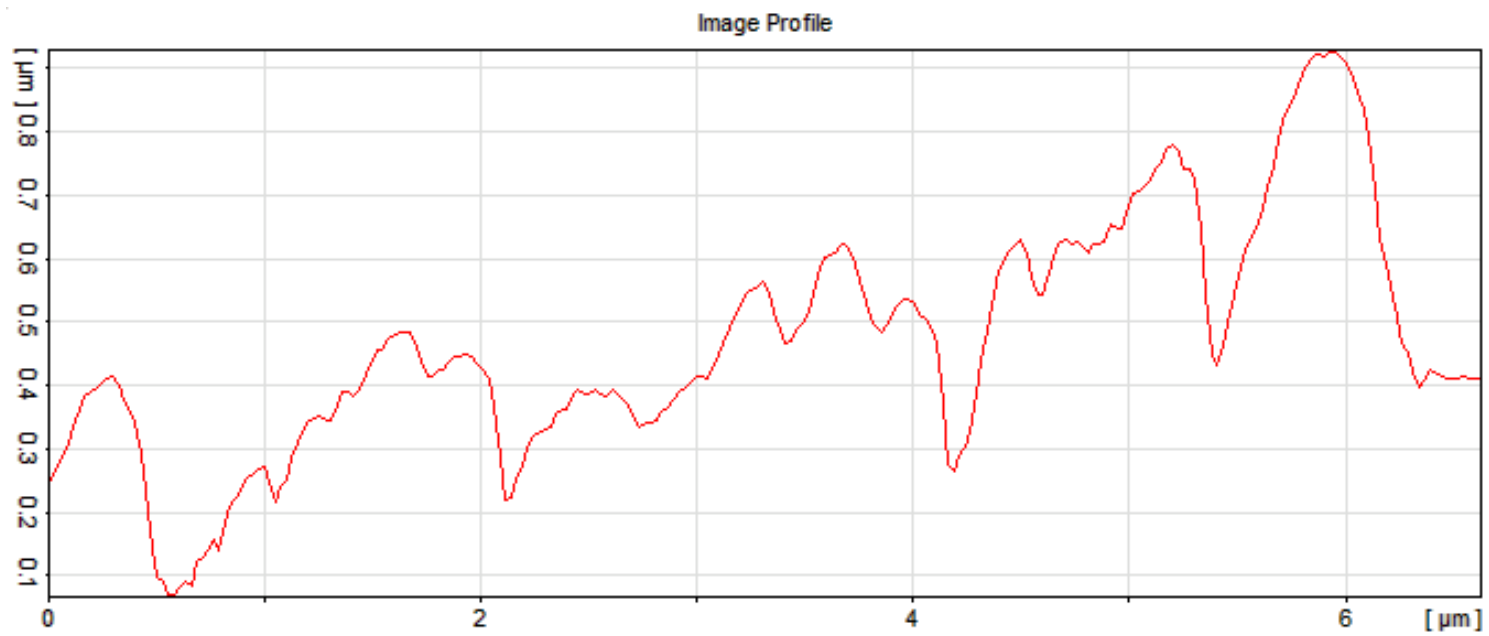
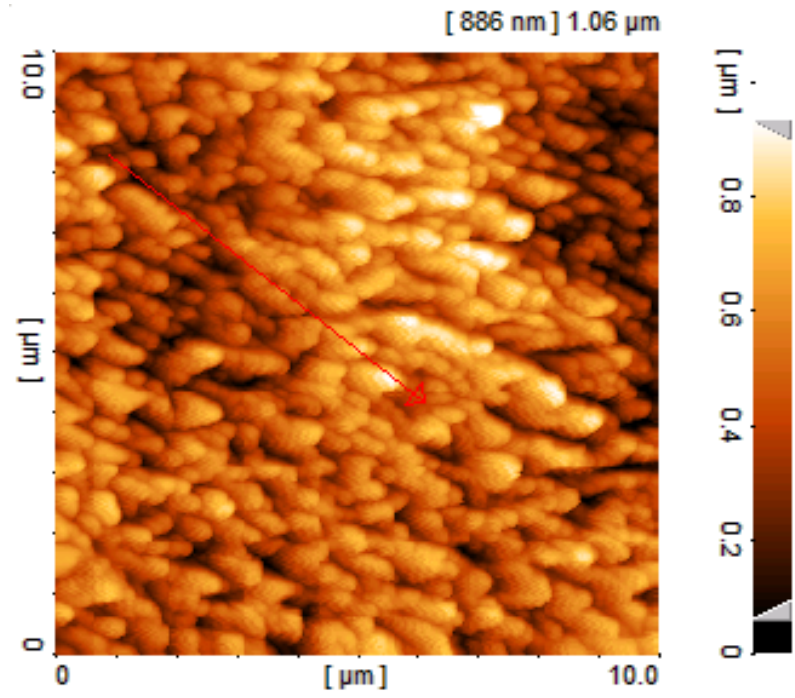


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.





EWEA AFM SAMPLES

L5 [L5-9]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

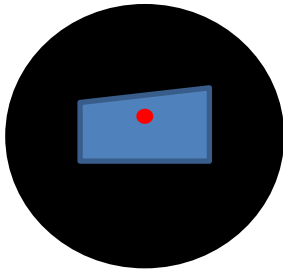
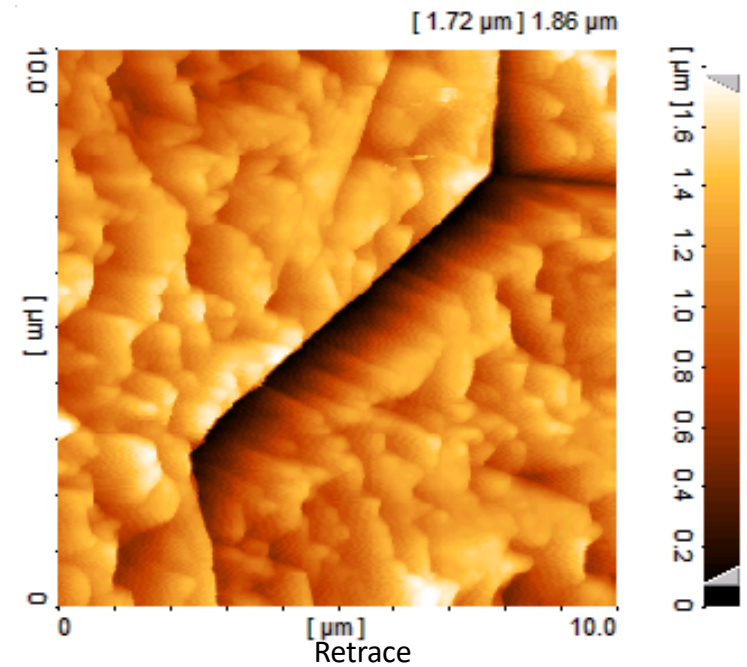
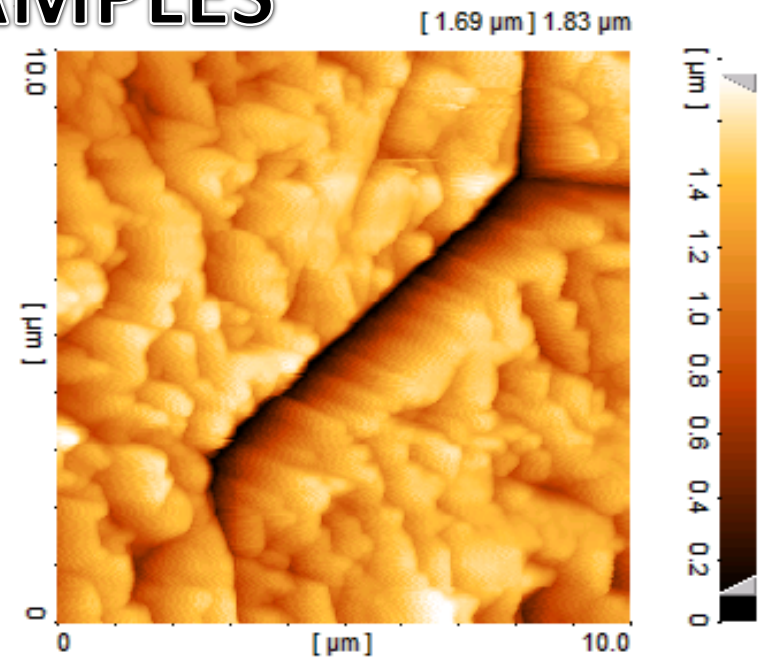
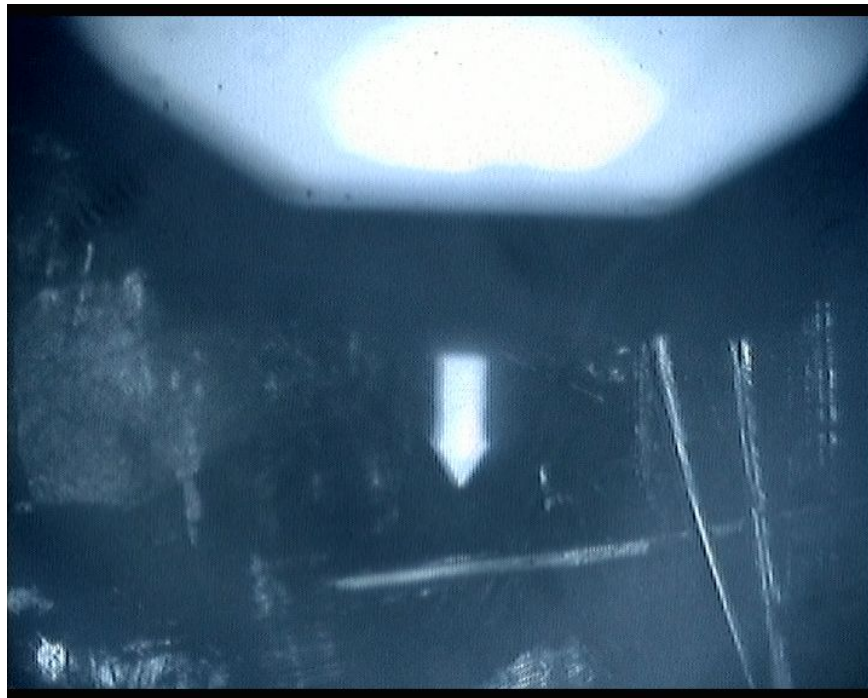
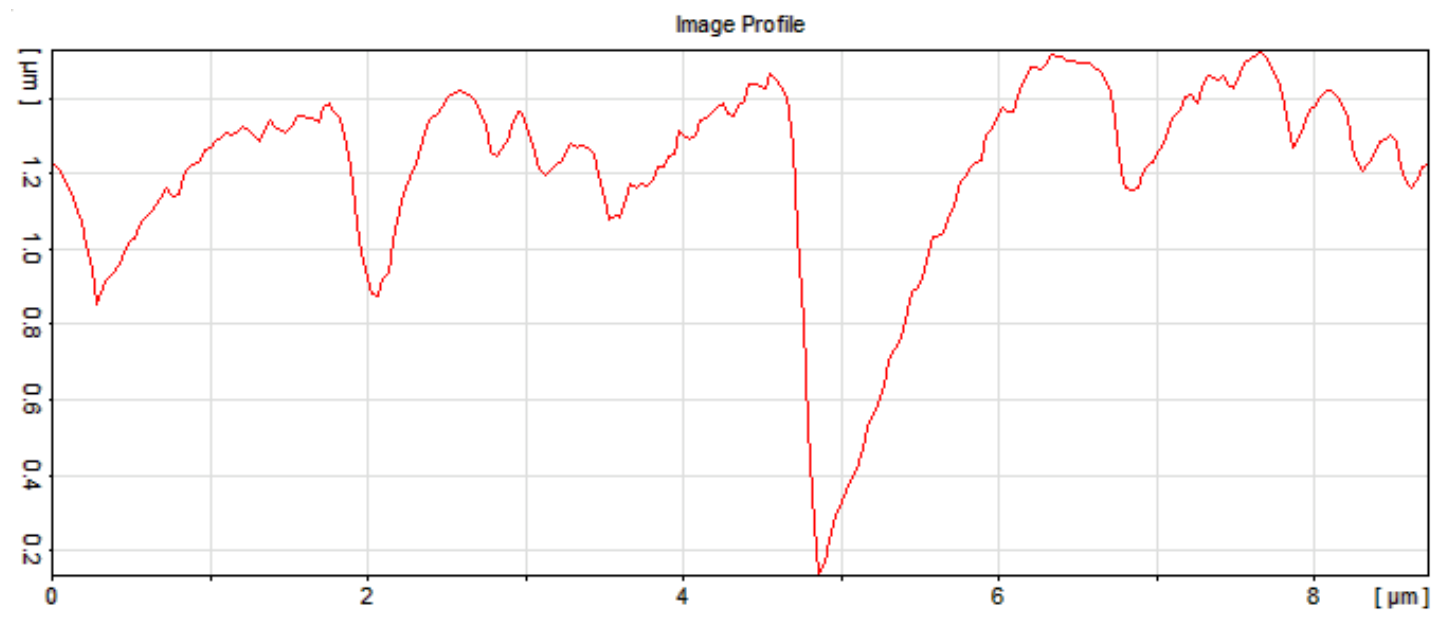
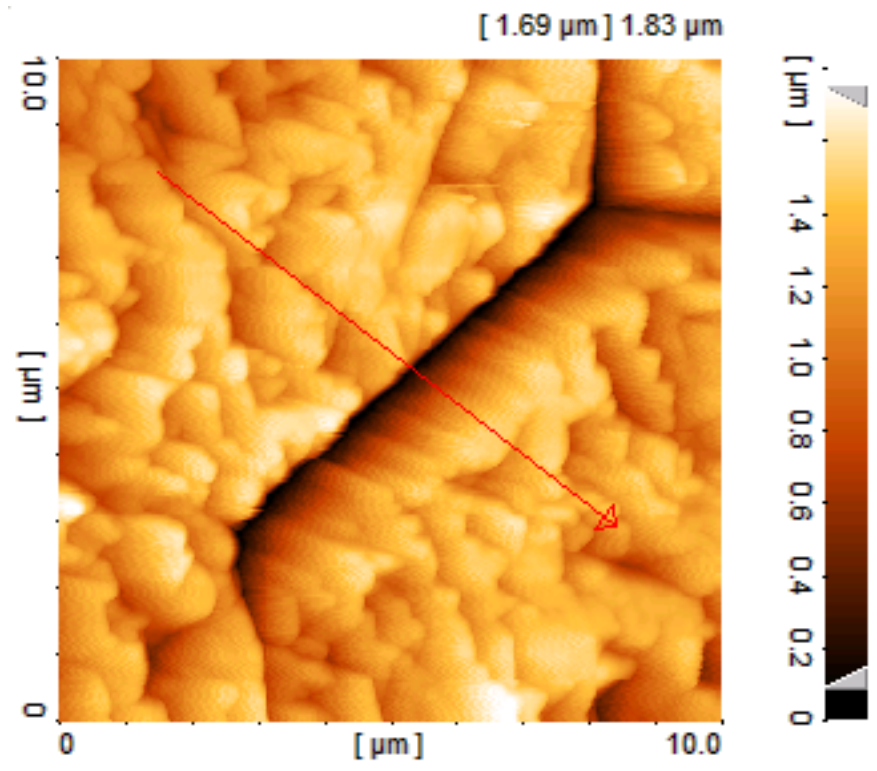


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.





EWEA AFM SAMPLES

L5 [L5-10]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

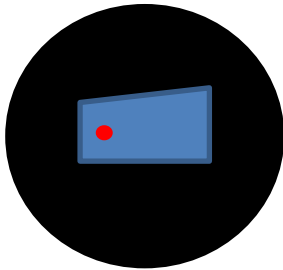
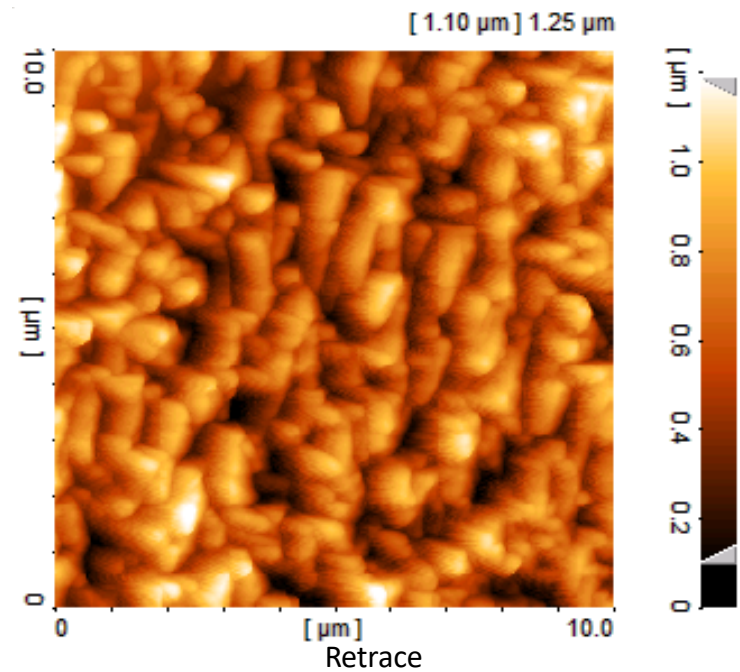
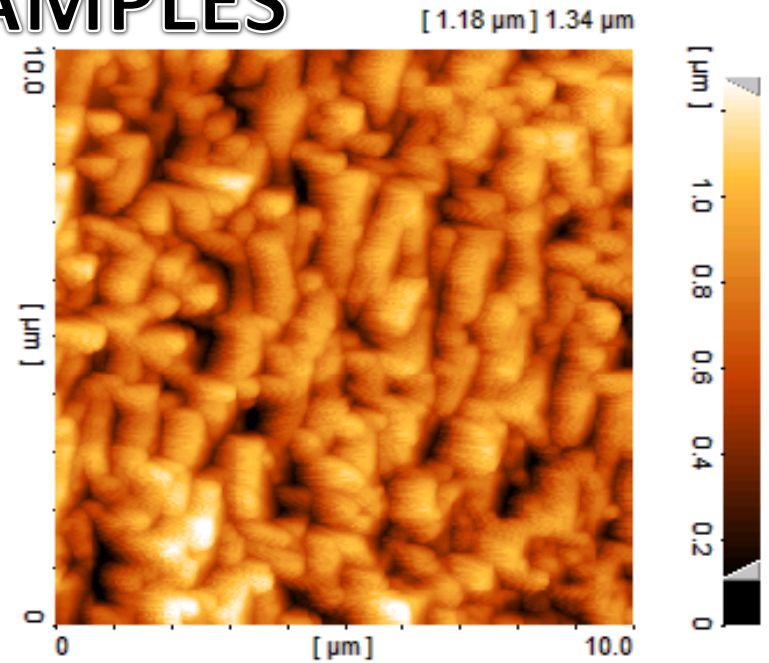
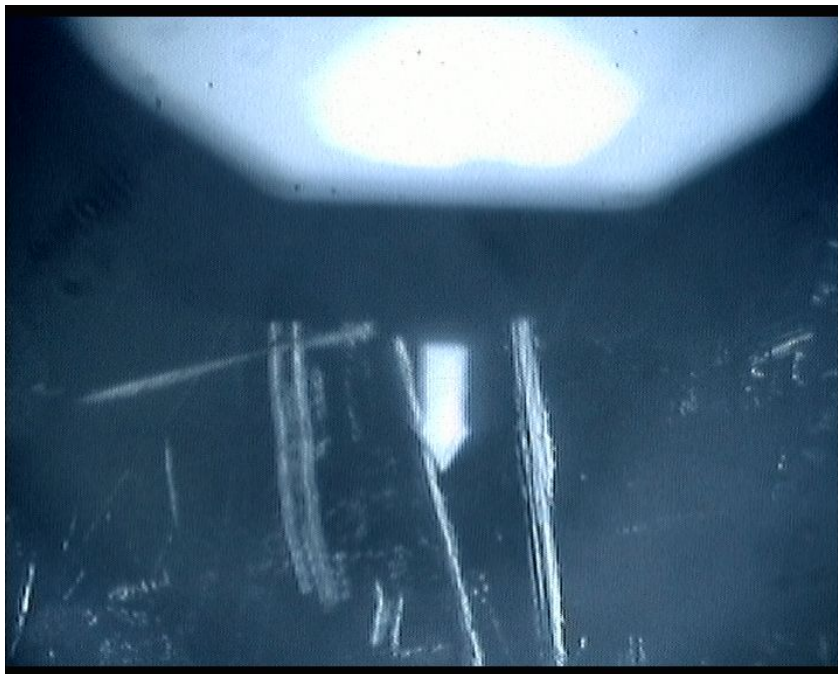


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.



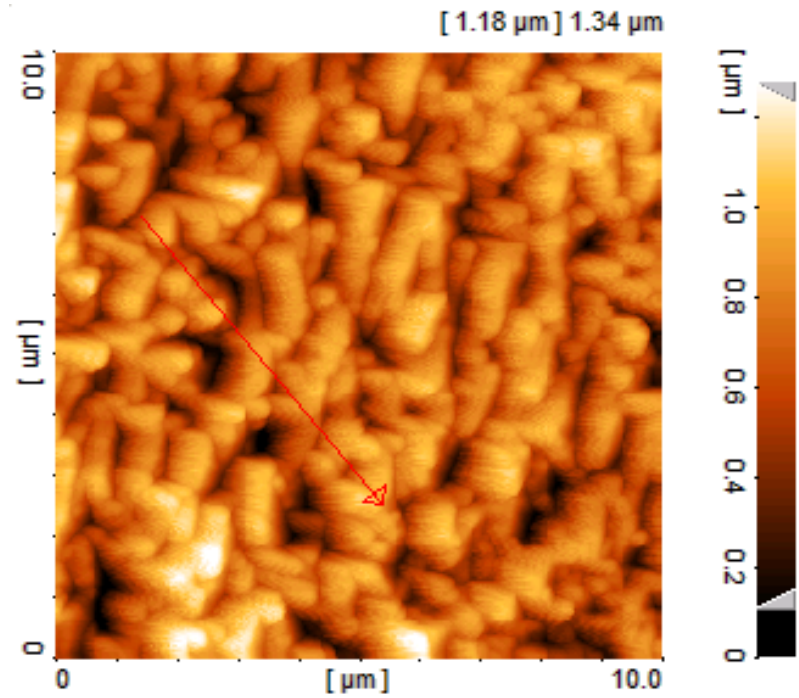
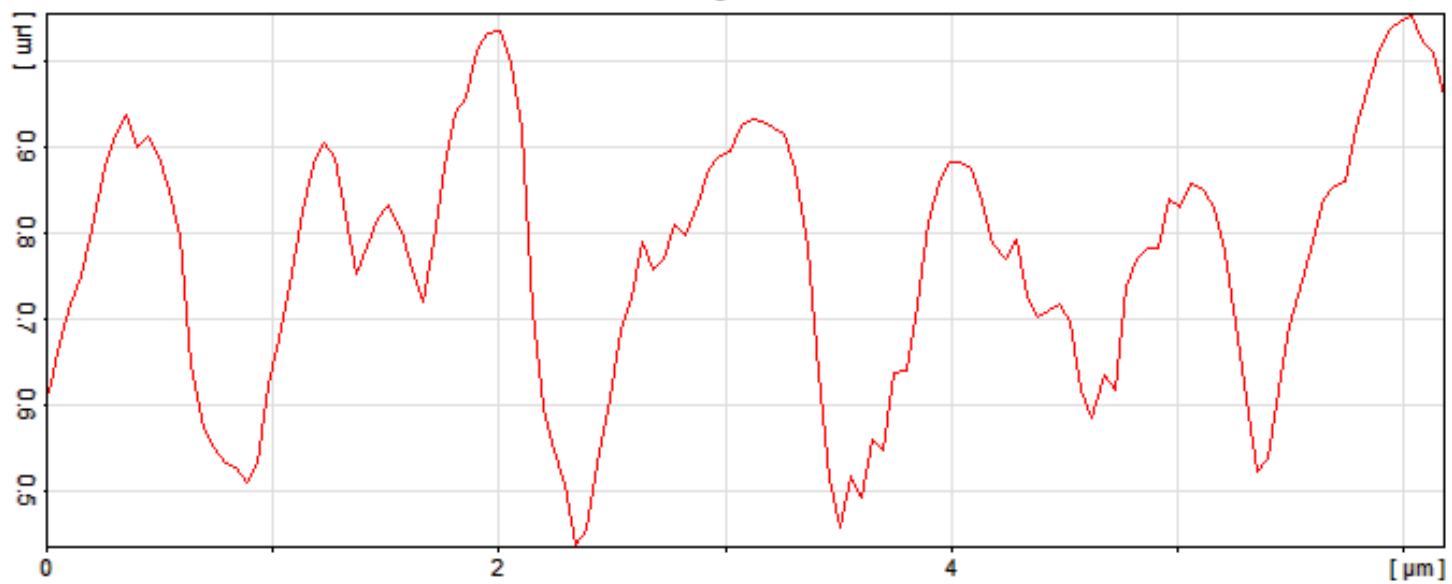


Image Profile



EWEA AFM SAMPLES

L5 [L5-11]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

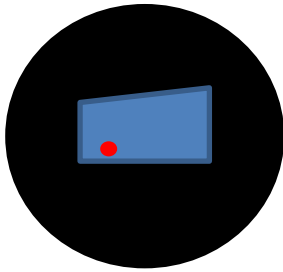
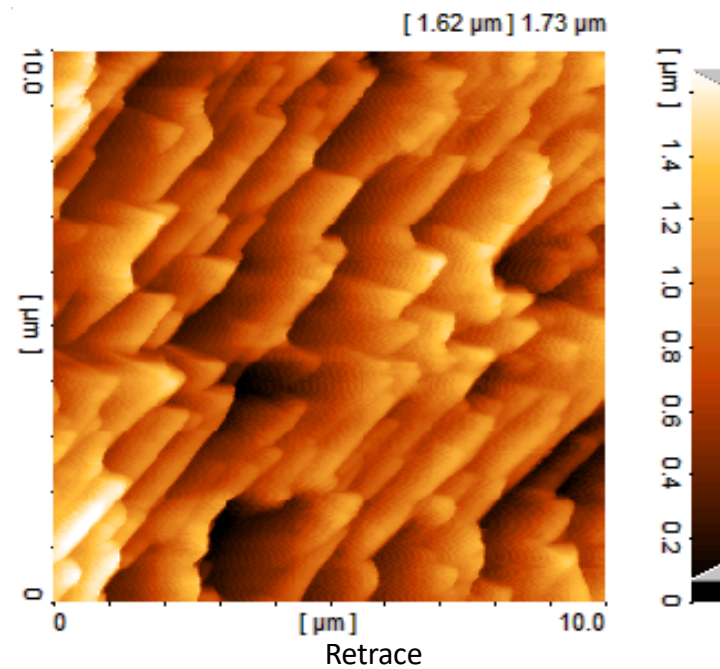
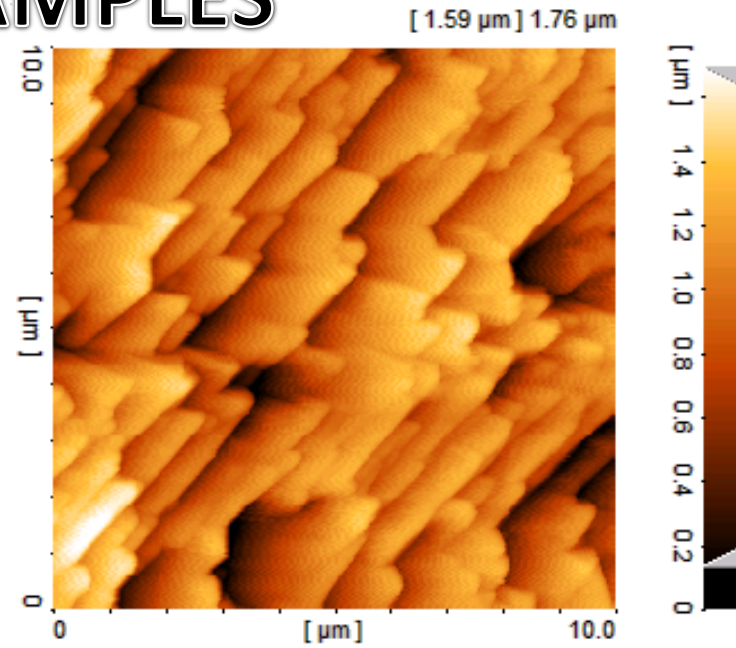
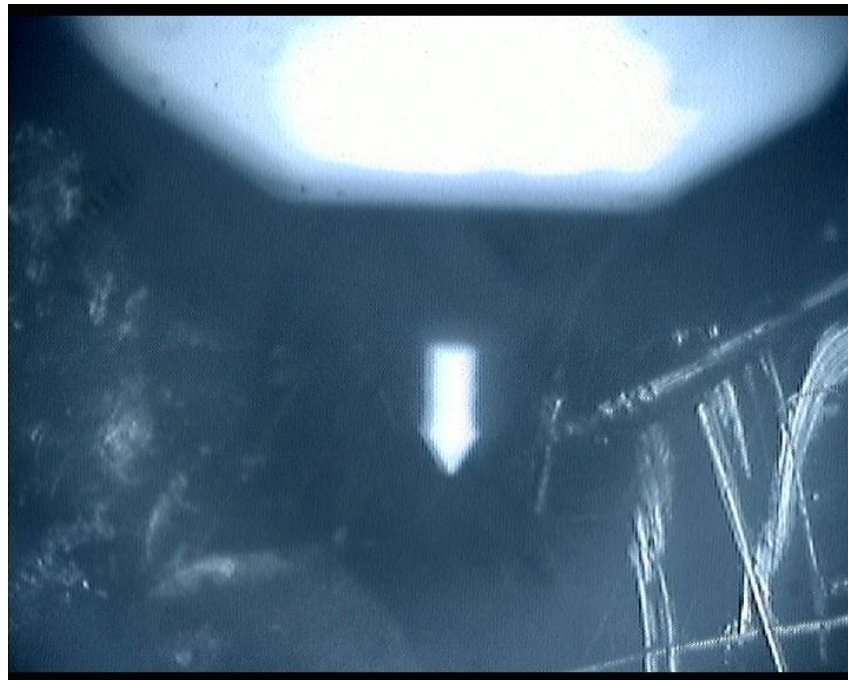
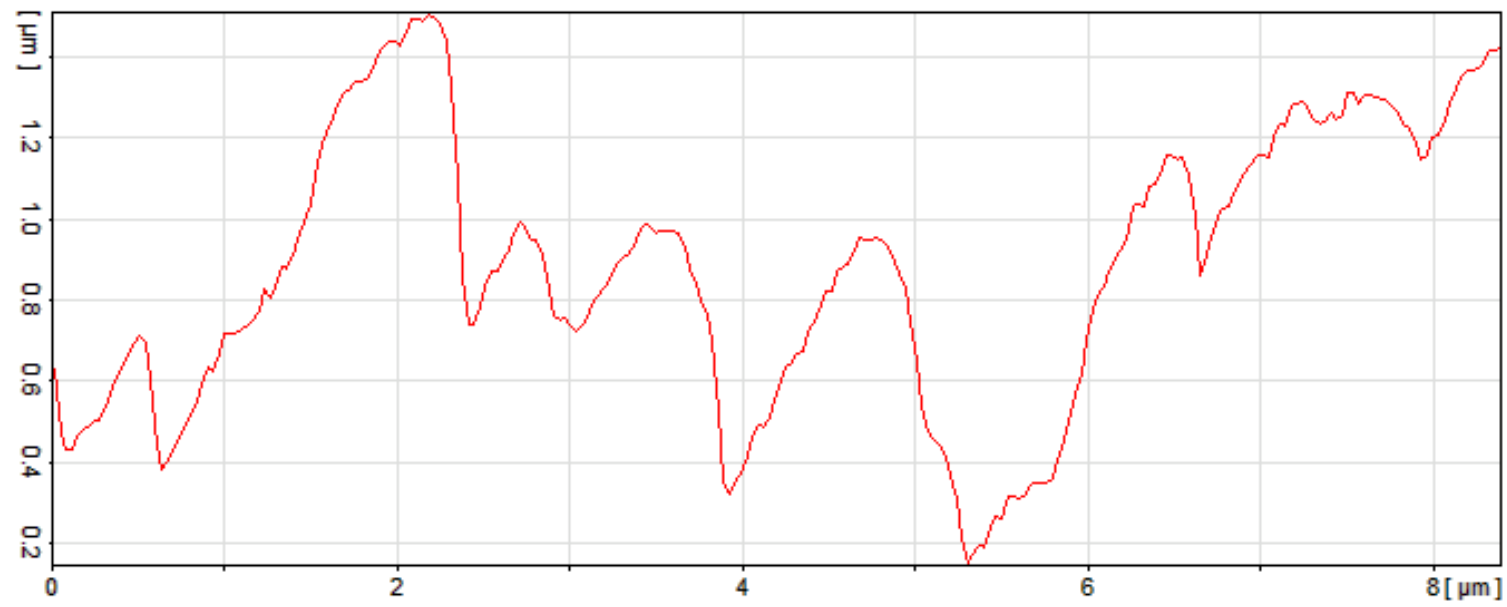
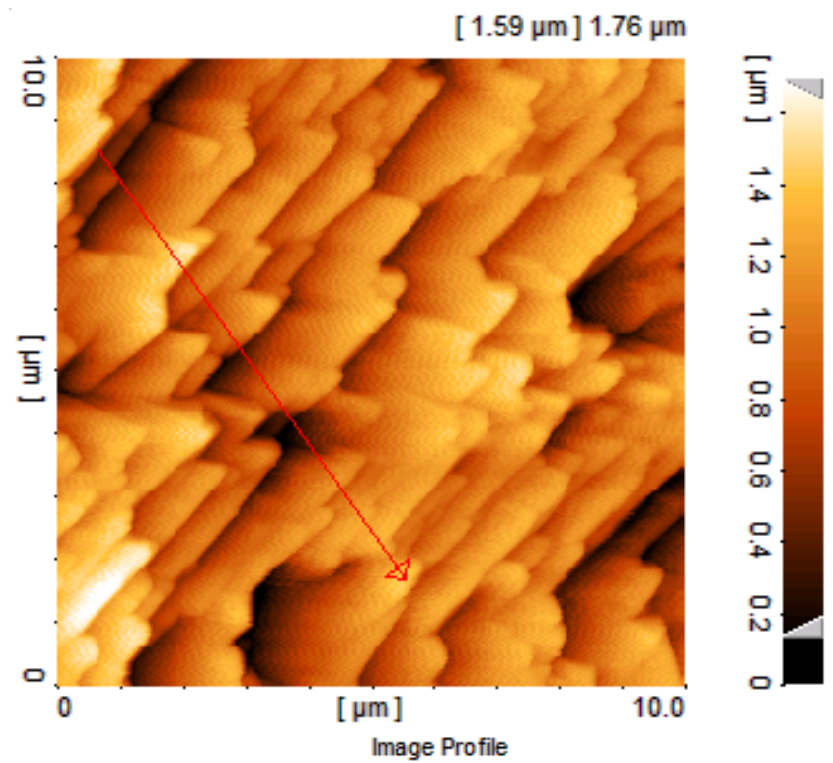


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.





EWEA AFM SAMPLES

L5 [L5-12]

256 pixels

10 μ m \times 10 μ m

Image was taken with a standard Silicon Tip.

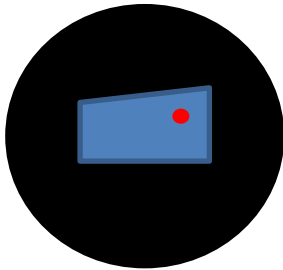
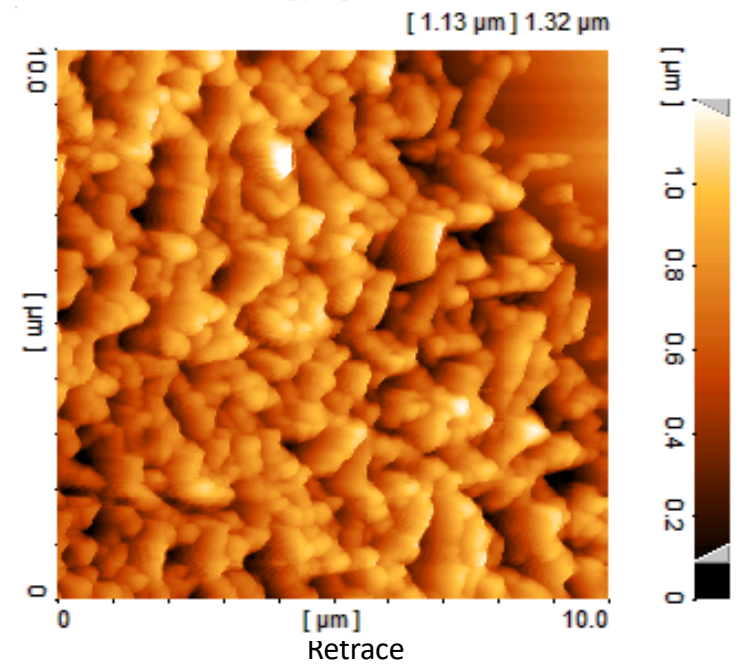
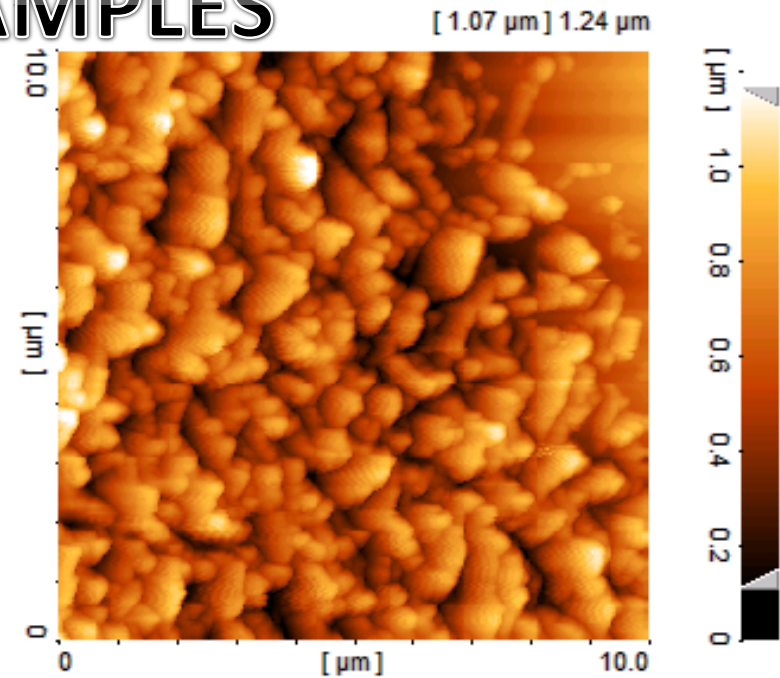
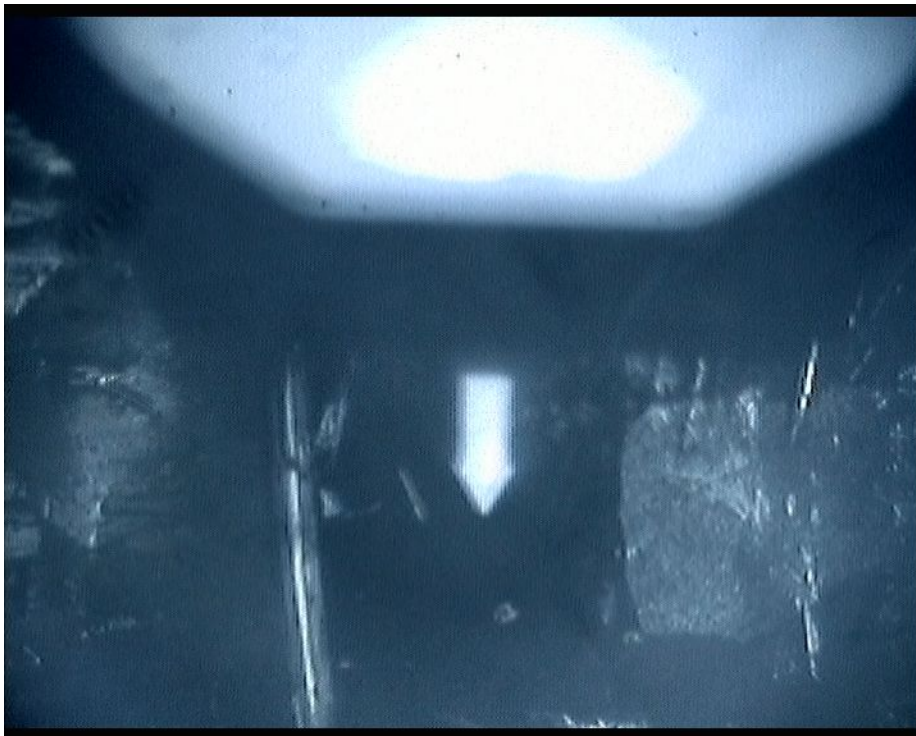


Diagram of sample on SEM stub

Red Circle indicates region of image taken by AFM.



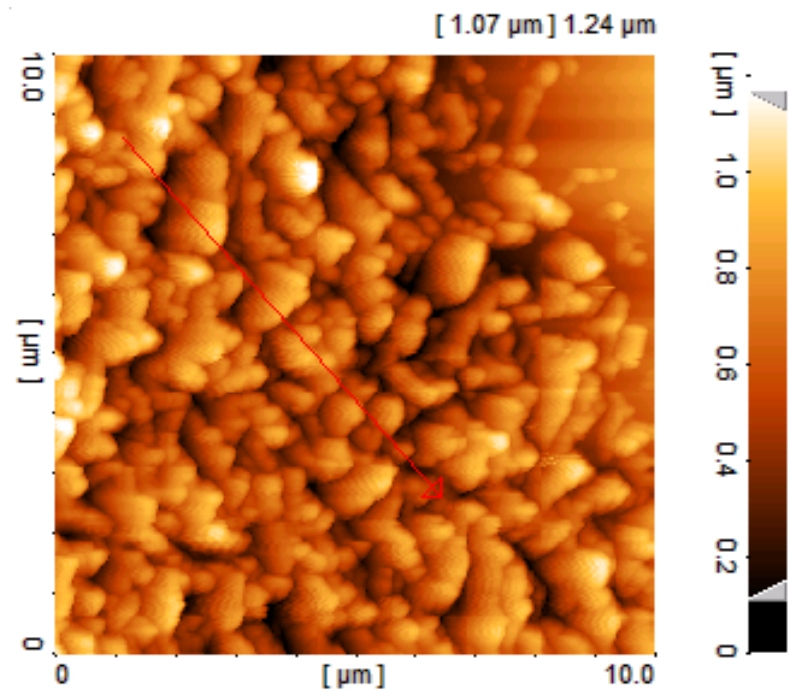


Image Profile

